

CELLULOSE/POLYSULFONE NANOCOMPOSITES

Sweda Noorani and John Simonsen

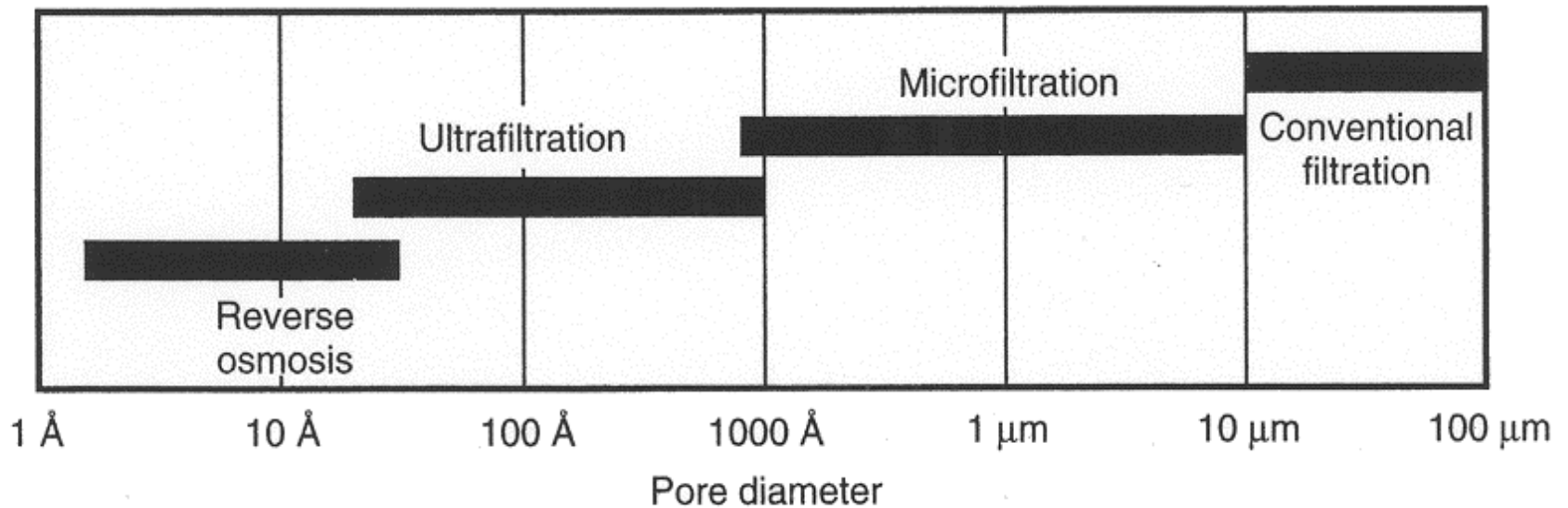
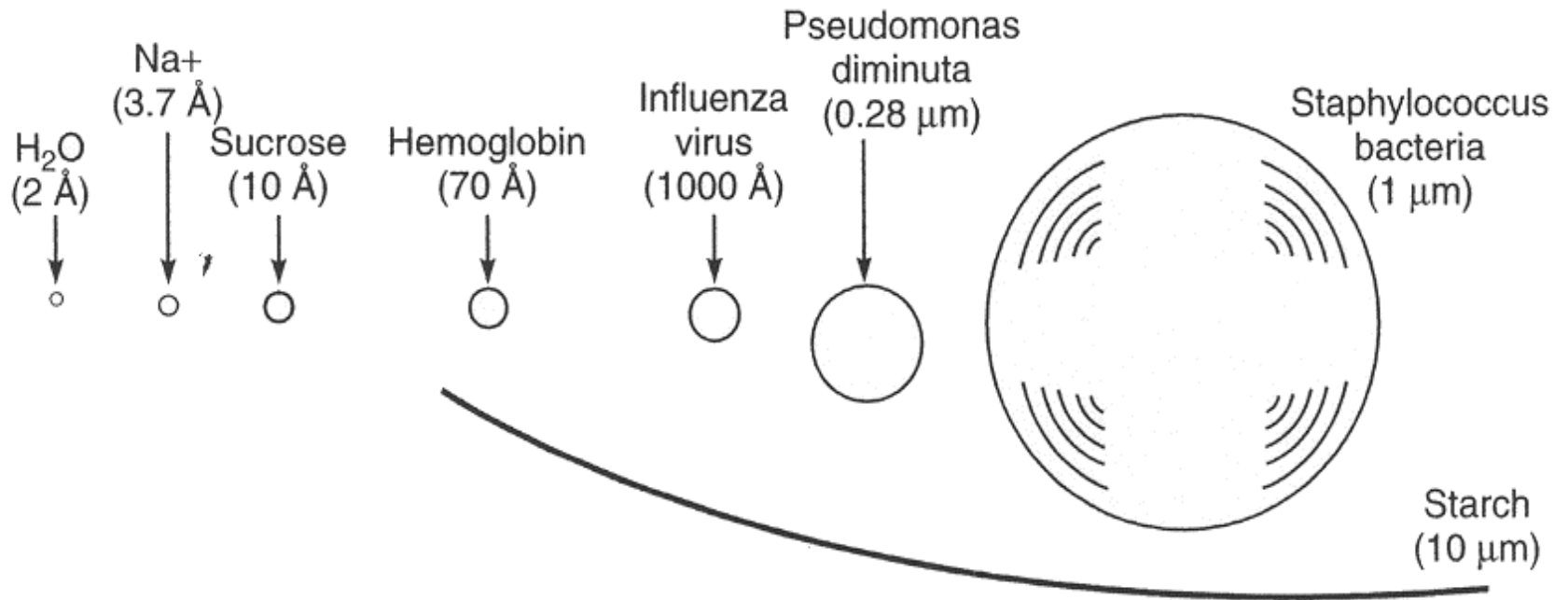
Oregon State University
Corvallis, Oregon

OREGON STATE
U n i v e r s i t y

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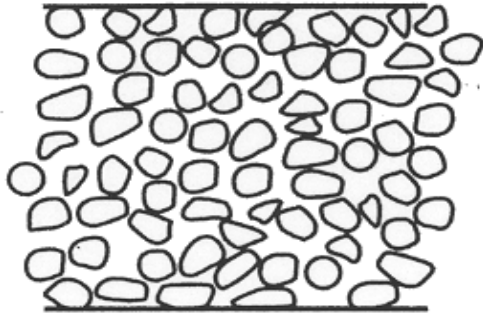
- Background
 - Membranes
 - MECS
- Experimental methods
- Results
- Conclusions
- Acknowledgements

Membranes

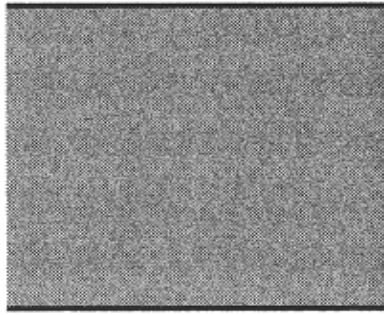


Symmetrical membranes

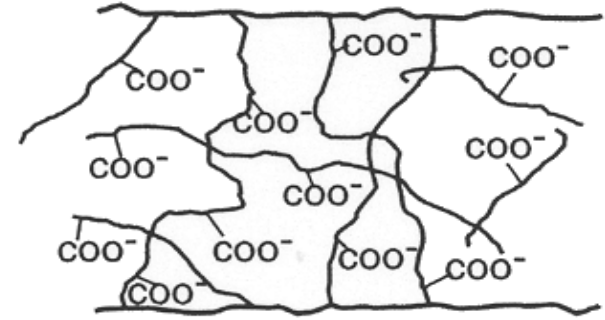
Isotropic microporous membrane



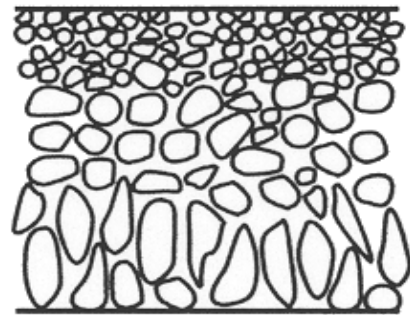
Nonporous dense membrane



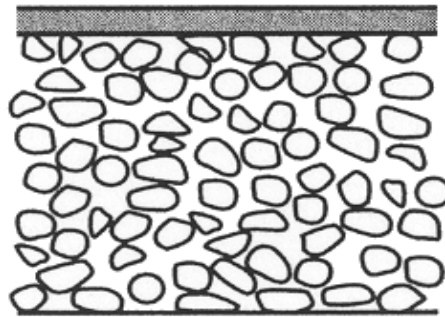
Electrically charged membrane



Anisotropic membranes



Loeb-Sourirajan anisotropic membrane



Thin-film composite anisotropic membrane

Supported liquid membrane

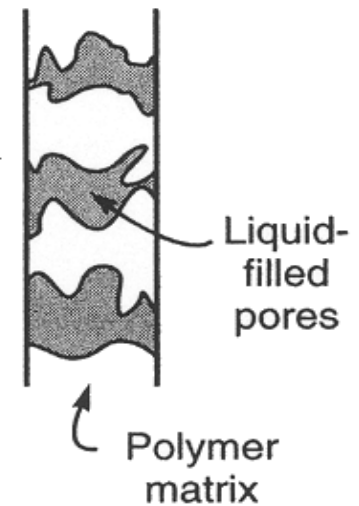
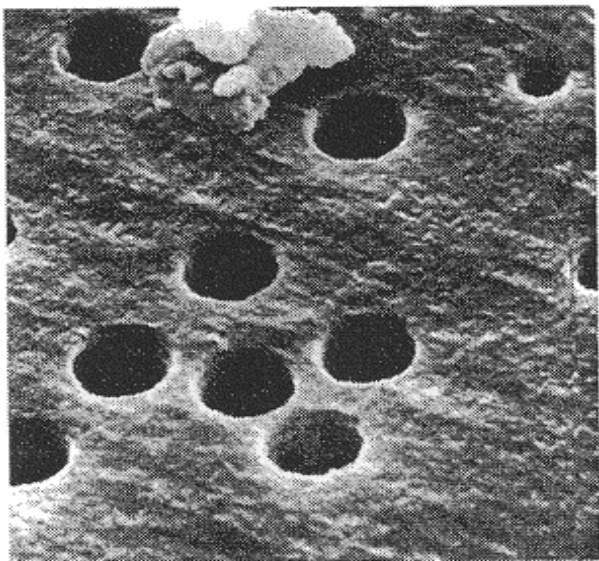
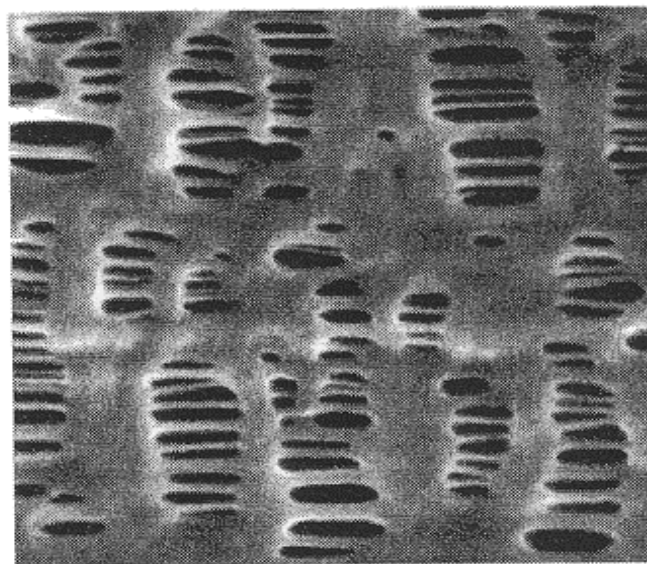


Figure 1.1 Schematic diagrams of the principal types of membranes

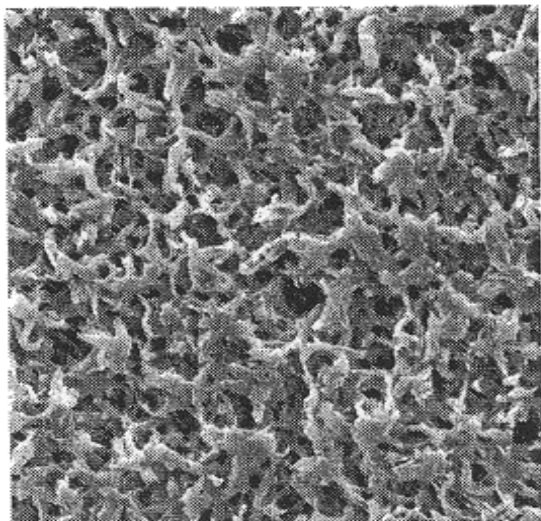
(a) Track etch



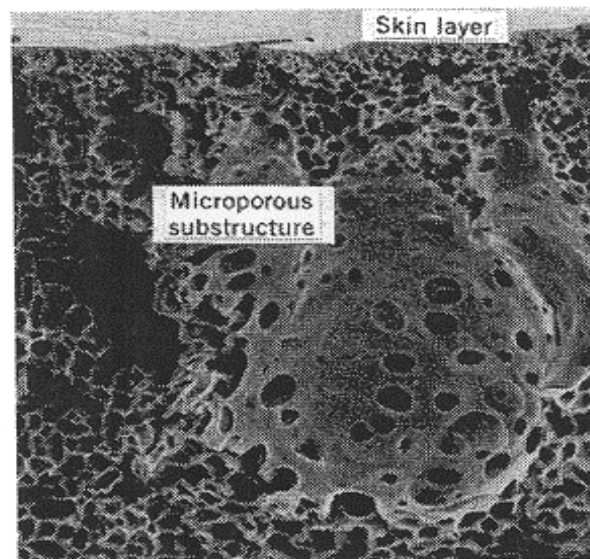
(b) Expanded film



(c) Phase separation



(d) Loeb–Sourirajan

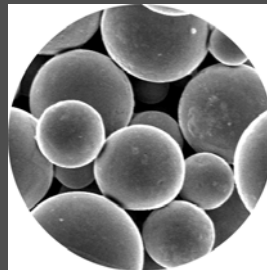
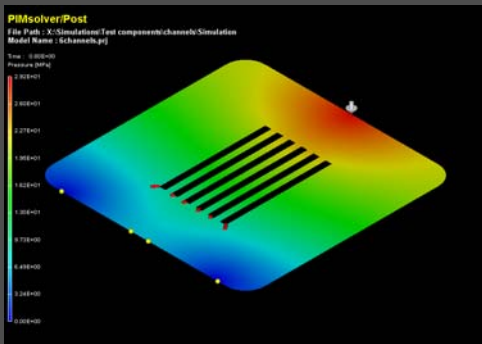


MECS

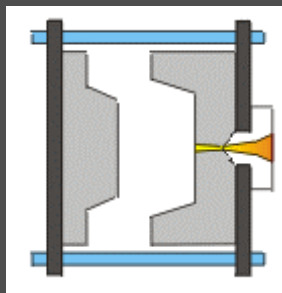
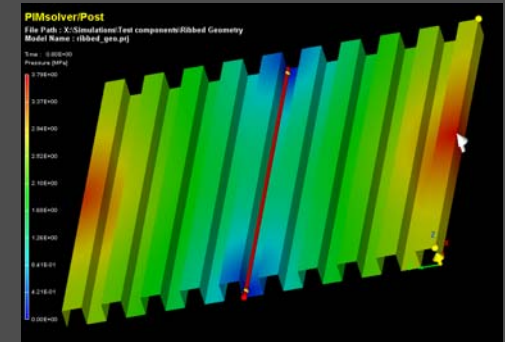
Microtechnologies in Energy
and Chemical Systems

Materials & Process Design for MECS

Prof. Sundar V. Atre

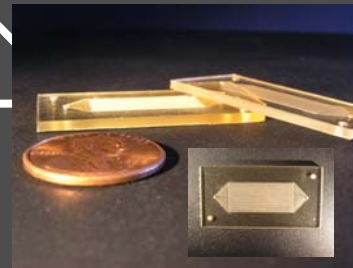


material
polymer
metal
ceramic
composite



process

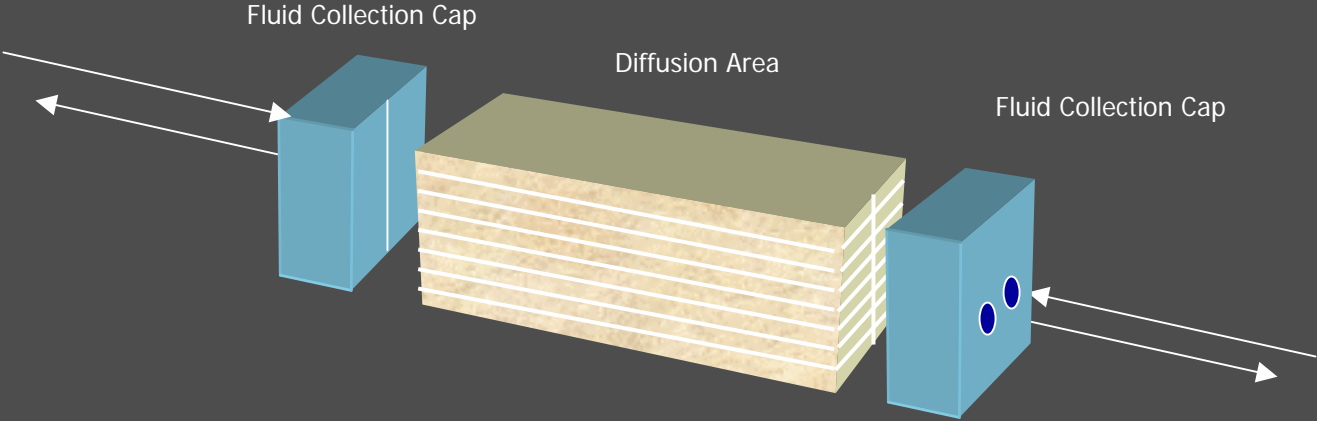
injection molding
extrusion
sintering
micromachining

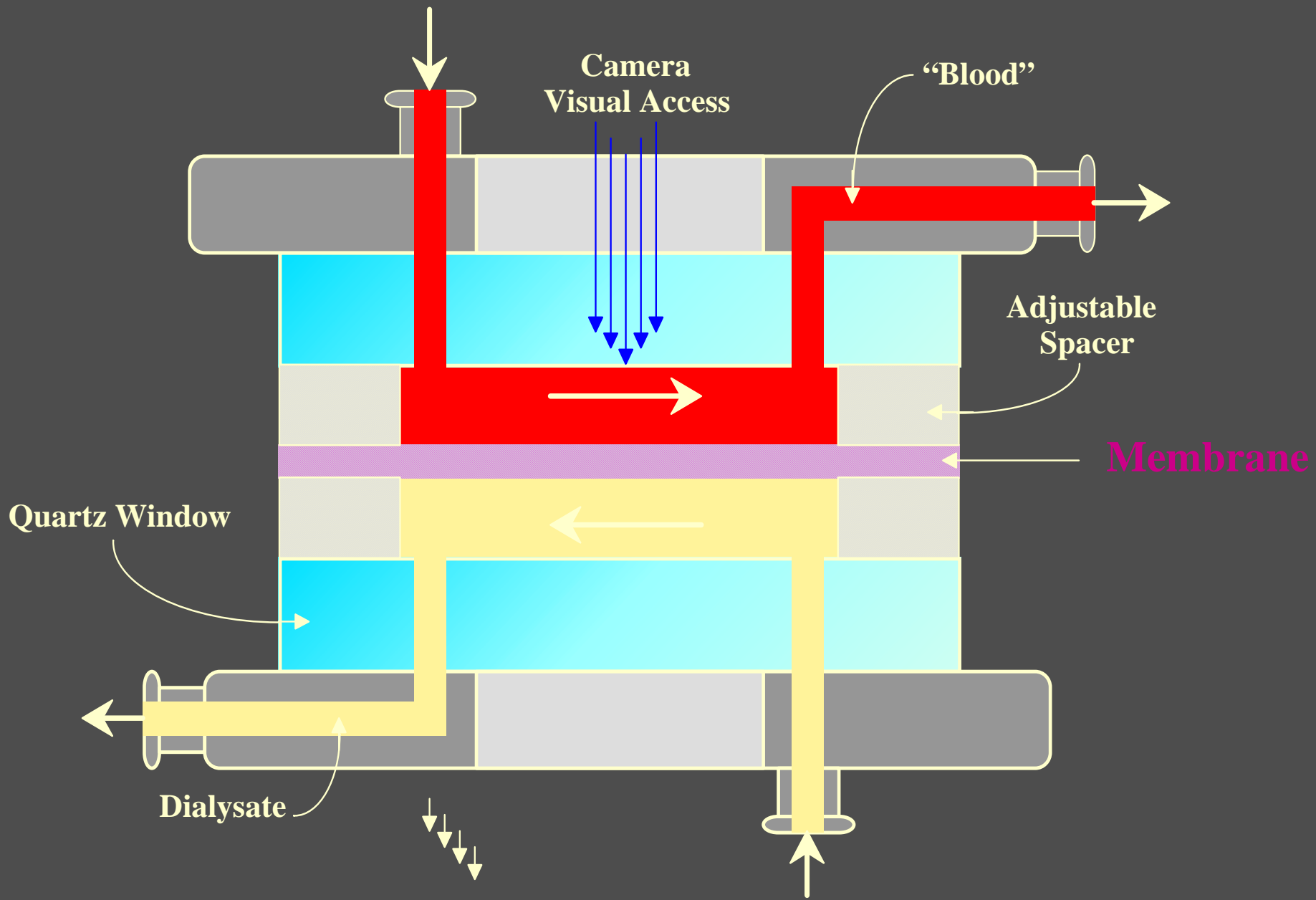


application

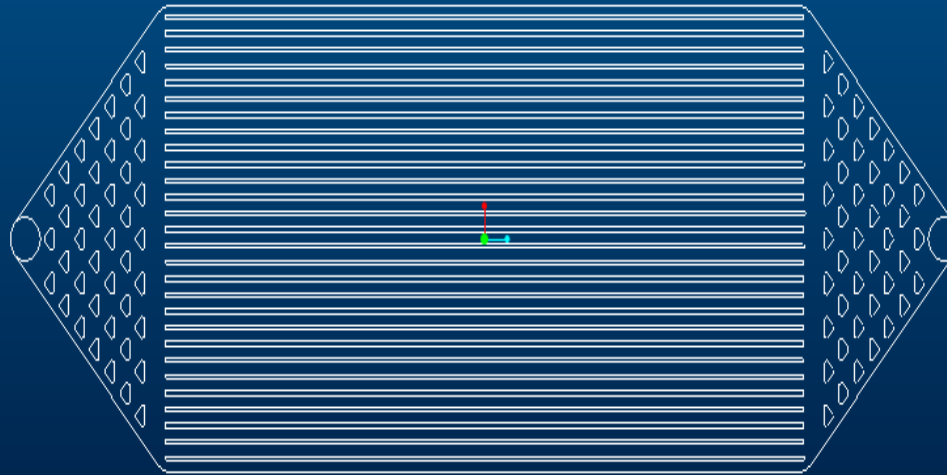
kidney dialysis
microreactor
thermal management
fuel cell

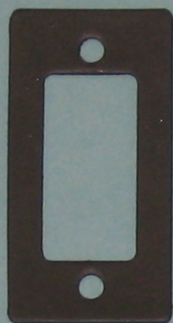
Dialyzer Unit Assembly Schematic

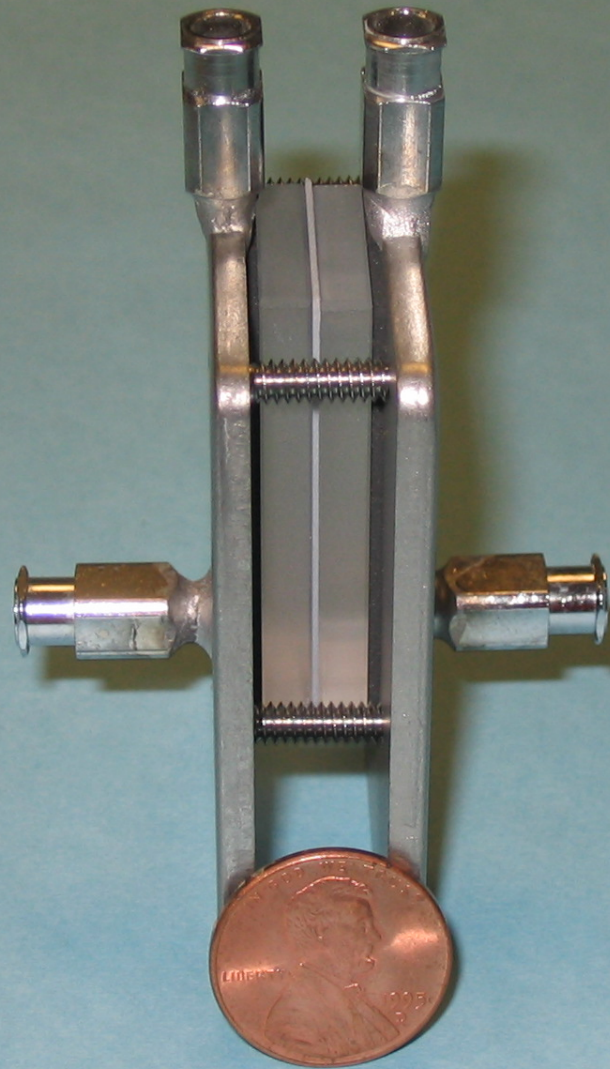




MECS Dialyzer Design



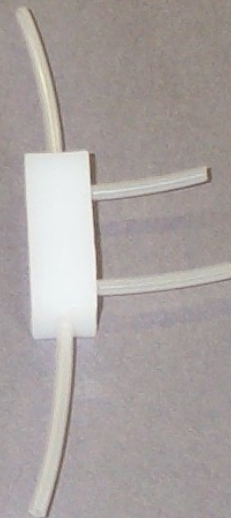






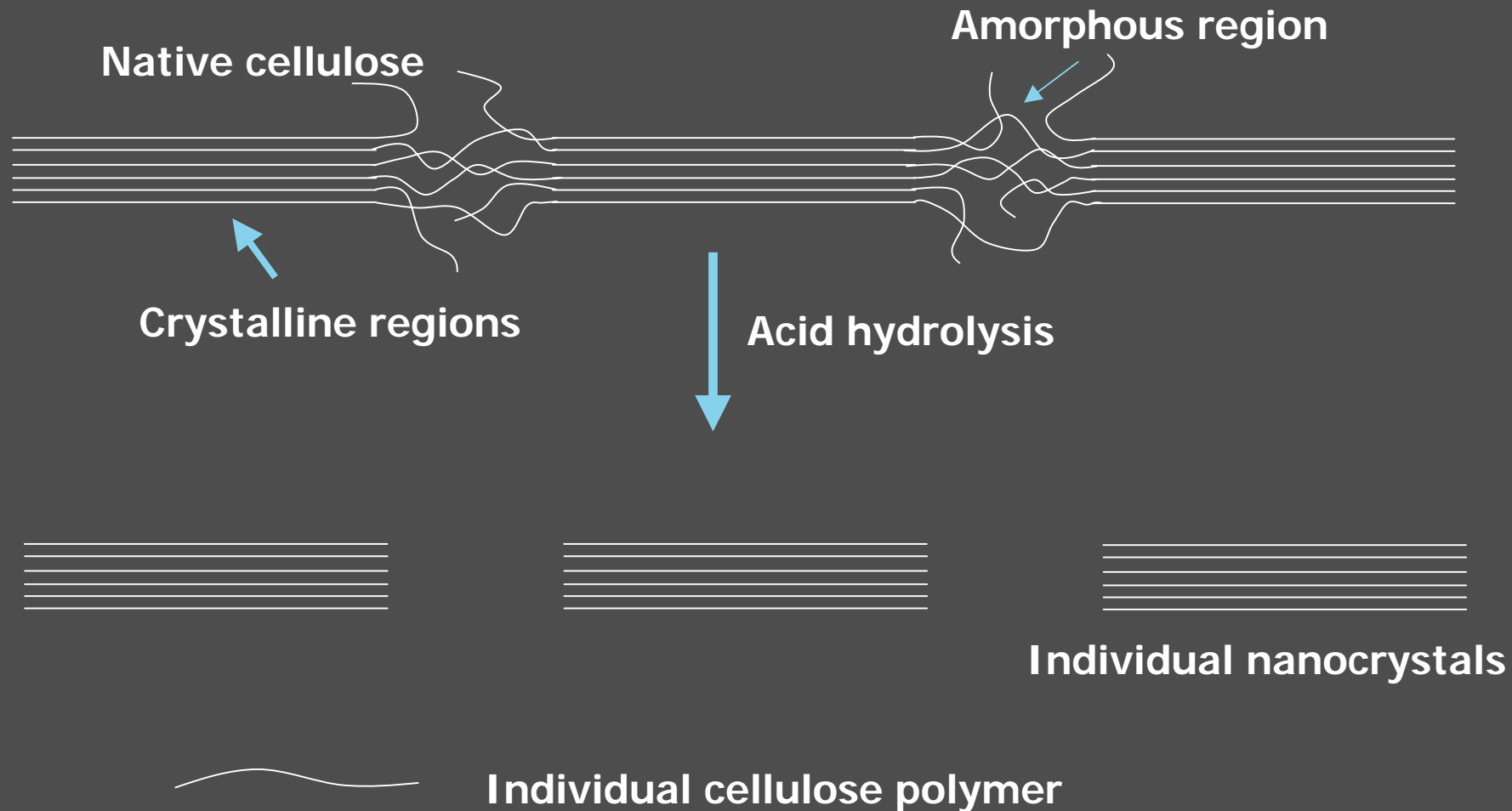
Hollow – fiber filter

MECS filter



Experimental Methods

Cellulose Nanocrystal Production



Polymer film preparation

- Solvent exchange to 1-methyl-2-pyrrolidone (NMP)
- Combine with polysulfone (PSf) in NMP
- Cast films two ways:
 - Coagulation via Loeb-Sourirajan anisotropic film
 - Solvent evaporation

Evaluation

⊗ Mechanical testing –Sintech 1G, Universal testing machine

- ◆ tensile test mode
- ◆ Data converted to stress-strain curves

⊗ Thermal Analysis

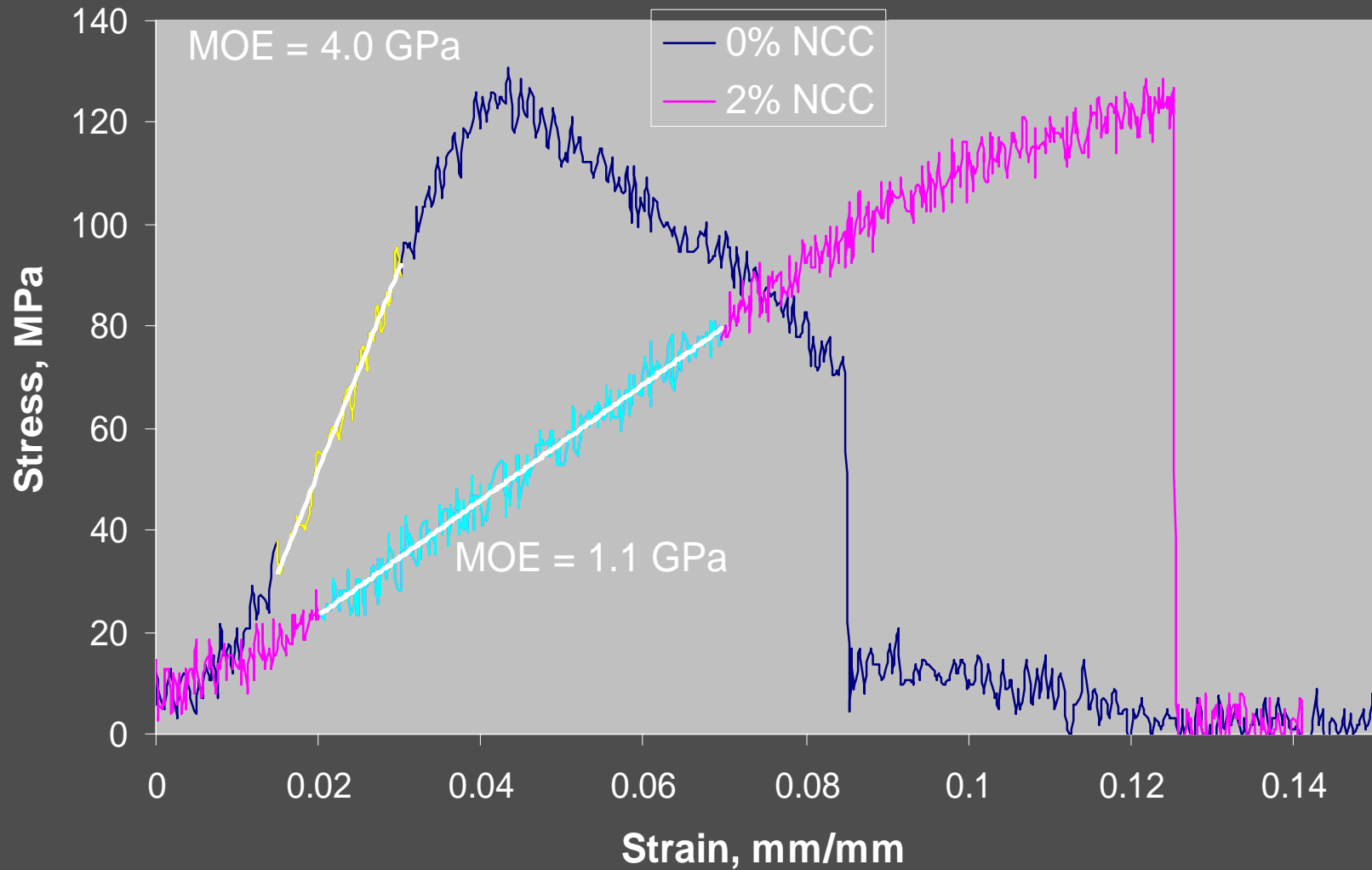
- ◆ Differential Scanning Calorimetry, TA Instruments DSC 2920
 - Temperature range – 20-250°C
 - Heating/cooling rate – 10 °C/min
- ◆ Thermo gravimetric analysis , TA Instruments, Q500
 - Temperature range – 40-600°C
 - Heating rate –10°C/min

Evaluation

- Scanning electron microscopy (SEM)
 - AMRay 1000A @ 10 kV
 - Coated with Au-Pd film (8-10 nm)
- Atomic force microscopy (AFM)
 - DI Dimension 3100 (Veeco Instruments)
 - Tapping mode

Mechanical properties

Stress-strain

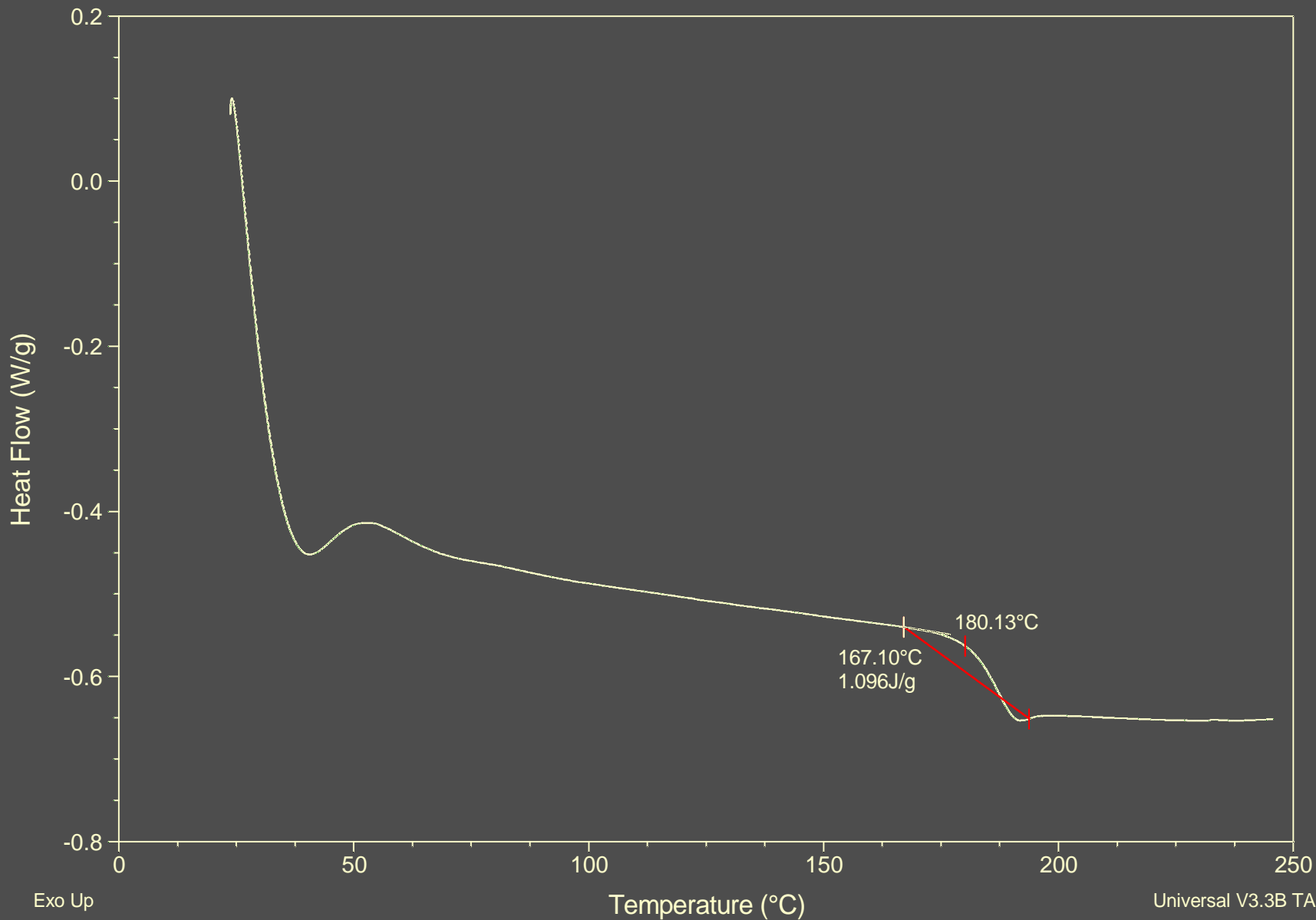


Thermal Properties

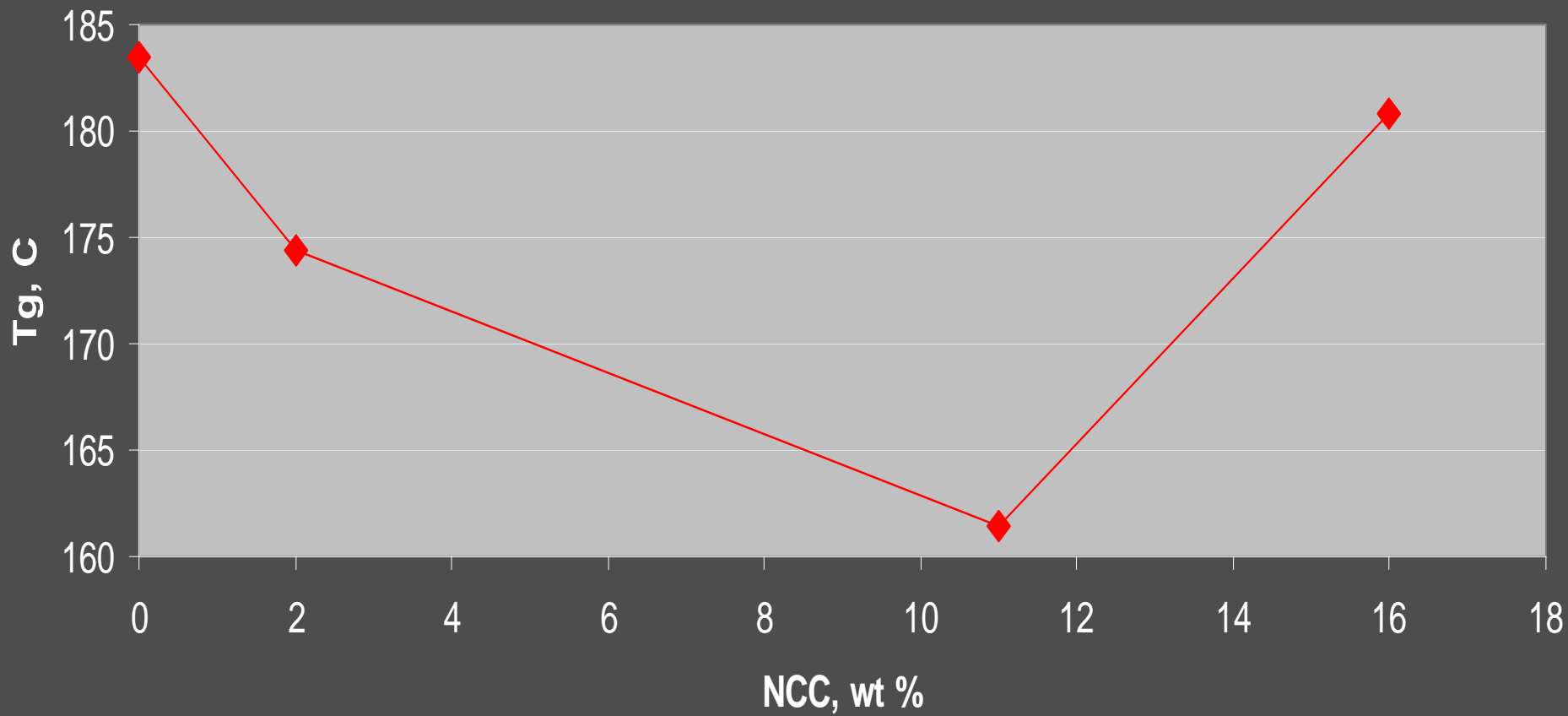
Sample: psf film nov 17,04
Size: 5.0000 mg
Method: Ramp
Comment: PSF FILM

DSC

File: C:\sweda\psf film nov 17,04(DSC).002
Operator: sweda
Run Date: 17-Nov-04 15:23
Instrument: 2920 MDSC V2.6A



T_g of NCC-filled PSf

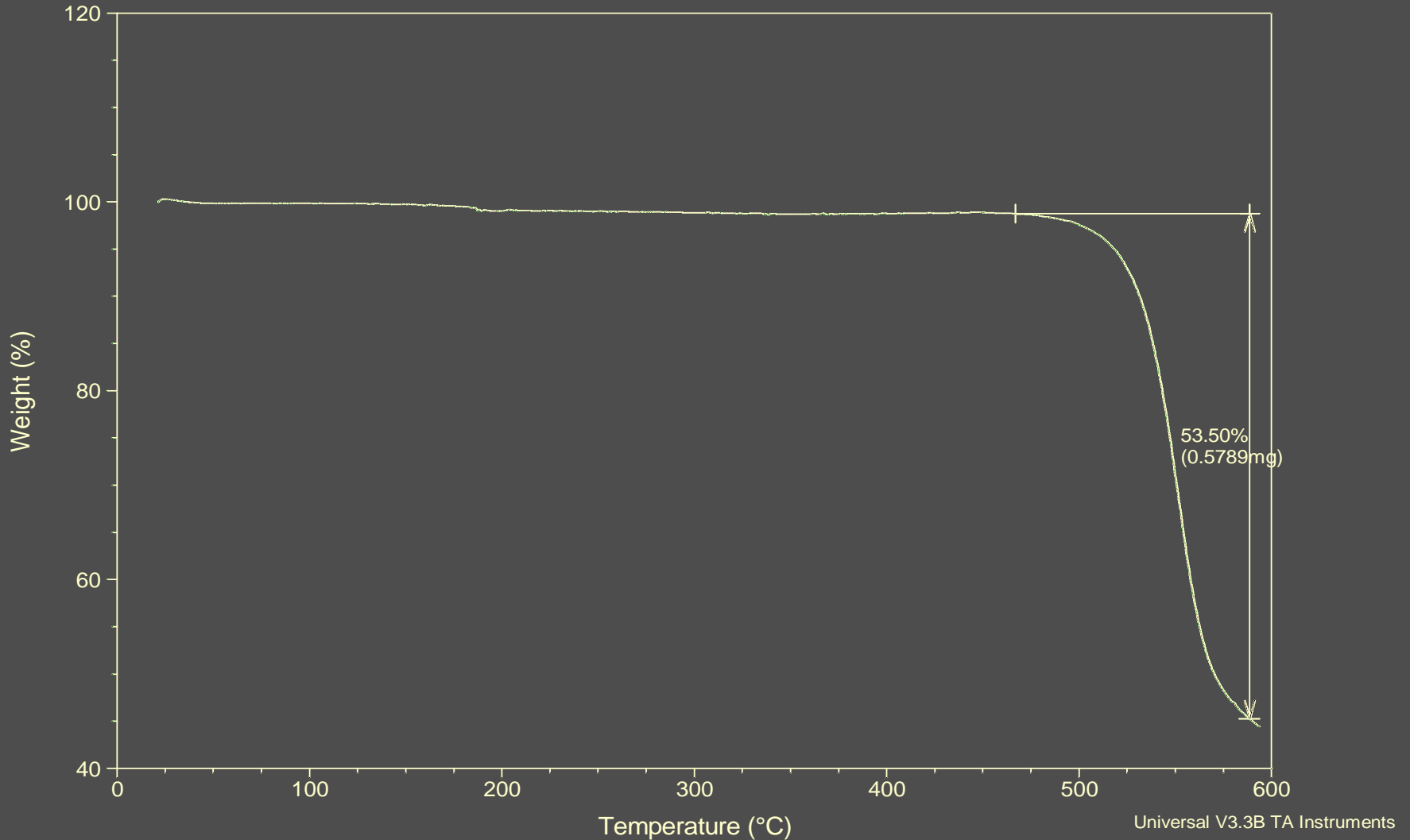


TGA Psf

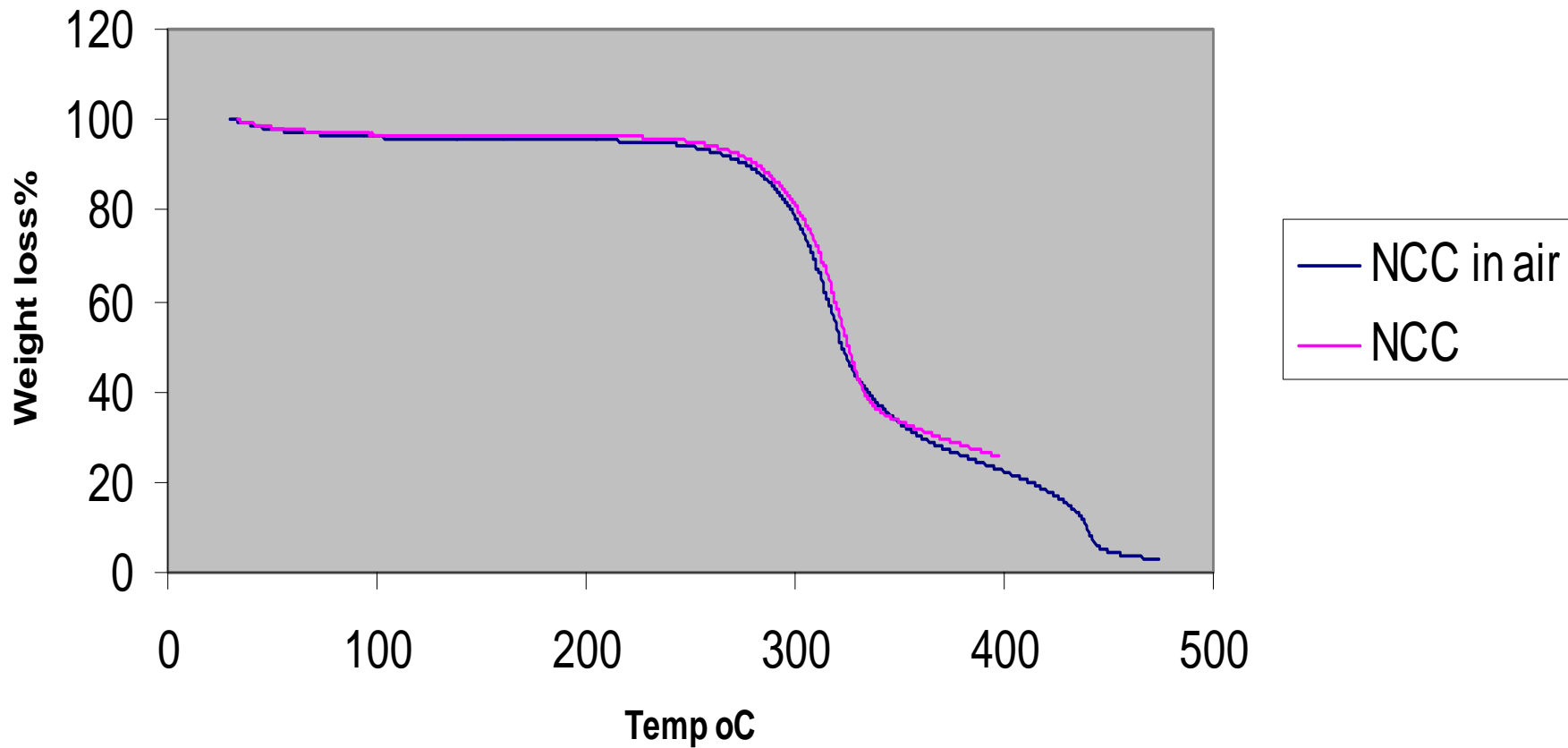
Sample: psf film nov 17, 04
Size: 1.0820 mg
Method: Ramp

TGA

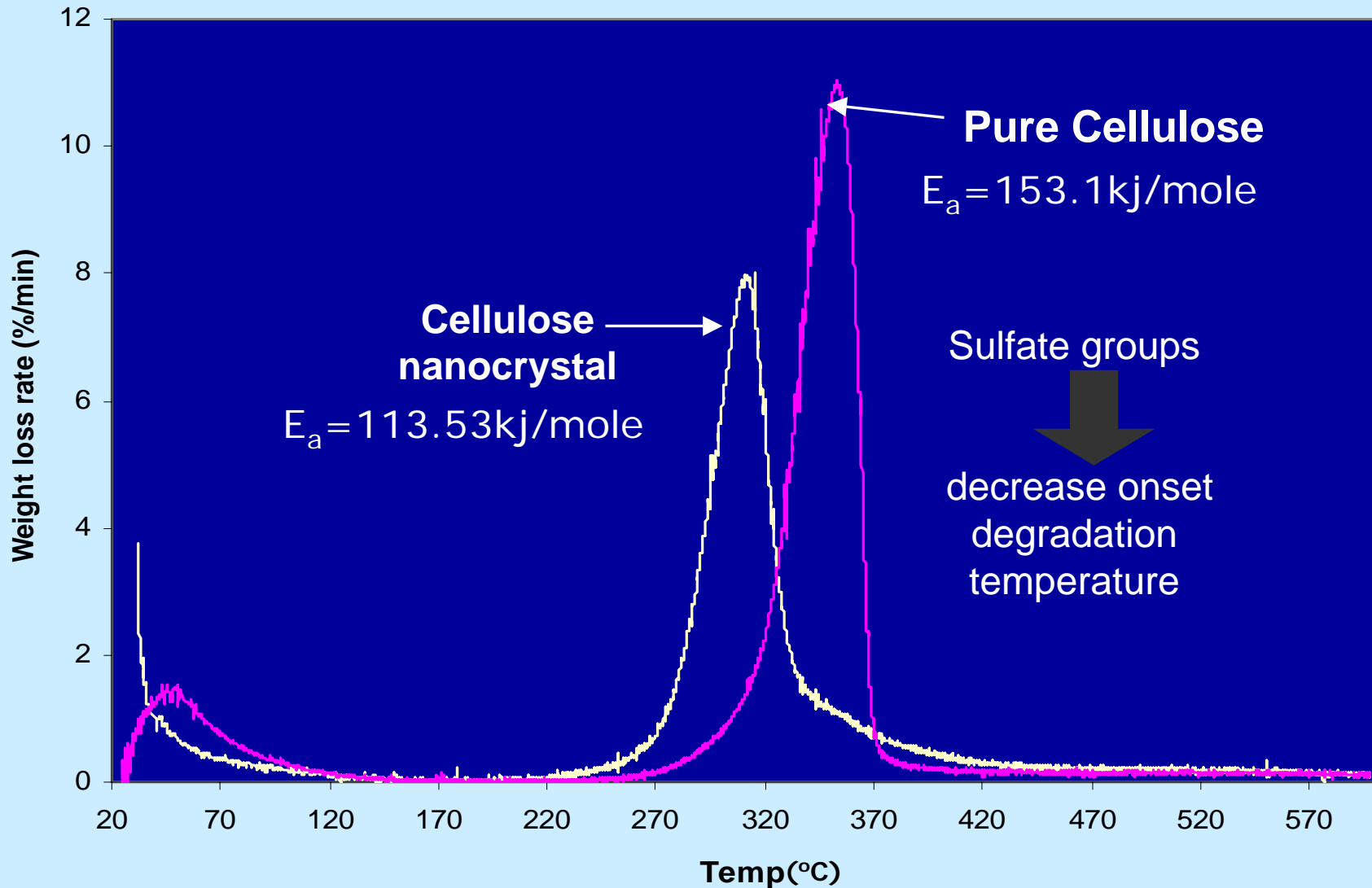
File: C:\Data\sweda\psf film nov 17,04.001
Operator: sweda
Run Date: 17-Nov-04 15:07
Instrument: 2950 TGA HR V6.0E



TGA of NCC in Nitrogen/air



Derivative Thermogravimetric (DTG) Curves

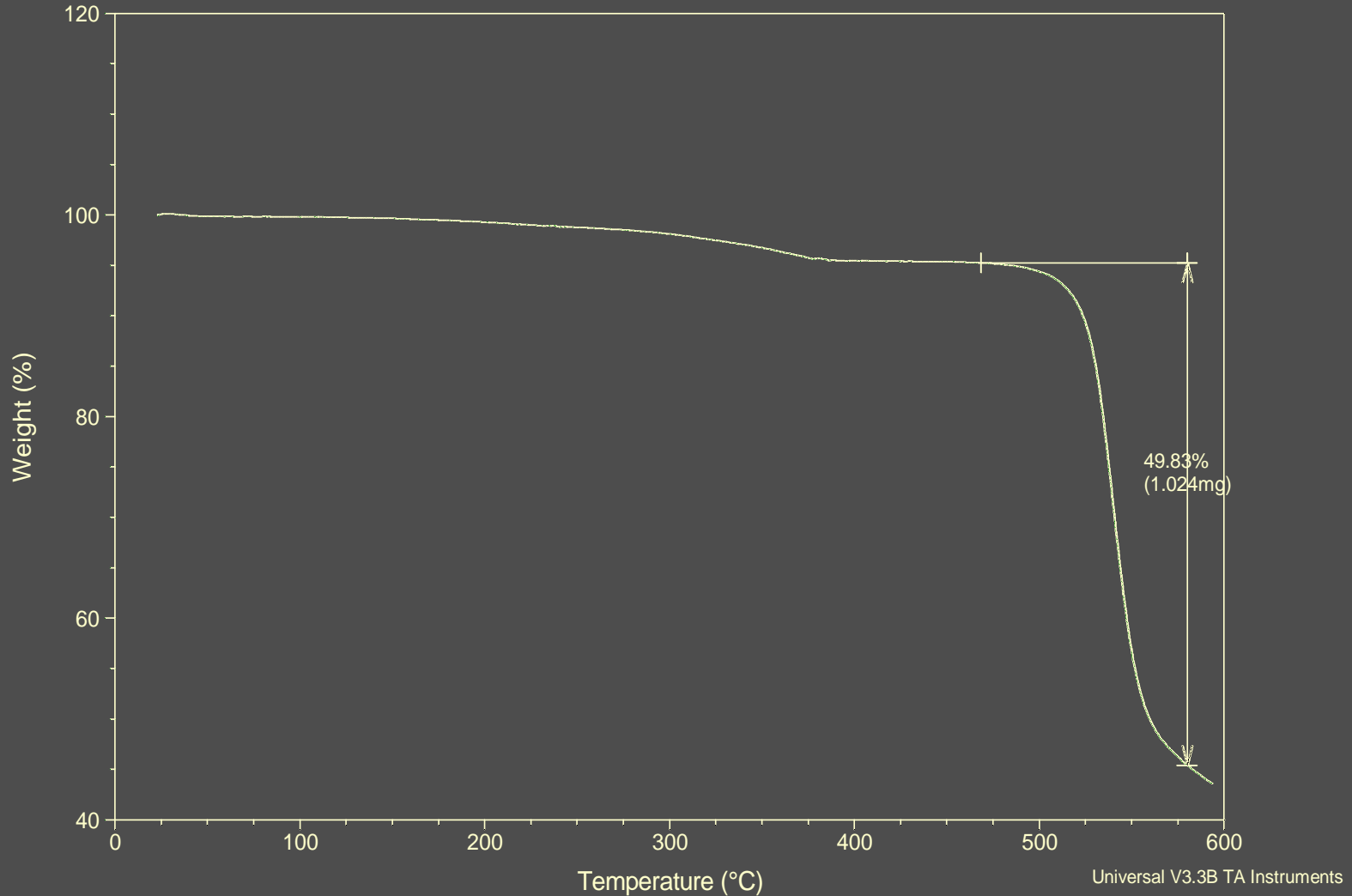


TGA (Psf film with 2% NCC)

Sample: psf film (ncc)nov 17, 04
Size: 2.0540 mg
Method: Ramp

TGA

File: C:\...sweda\psf film(ncc) nov 17,04.001
Operator: sweda
Run Date: 17-Nov-04 17:07
Instrument: 2950 TGA HR V6.0E

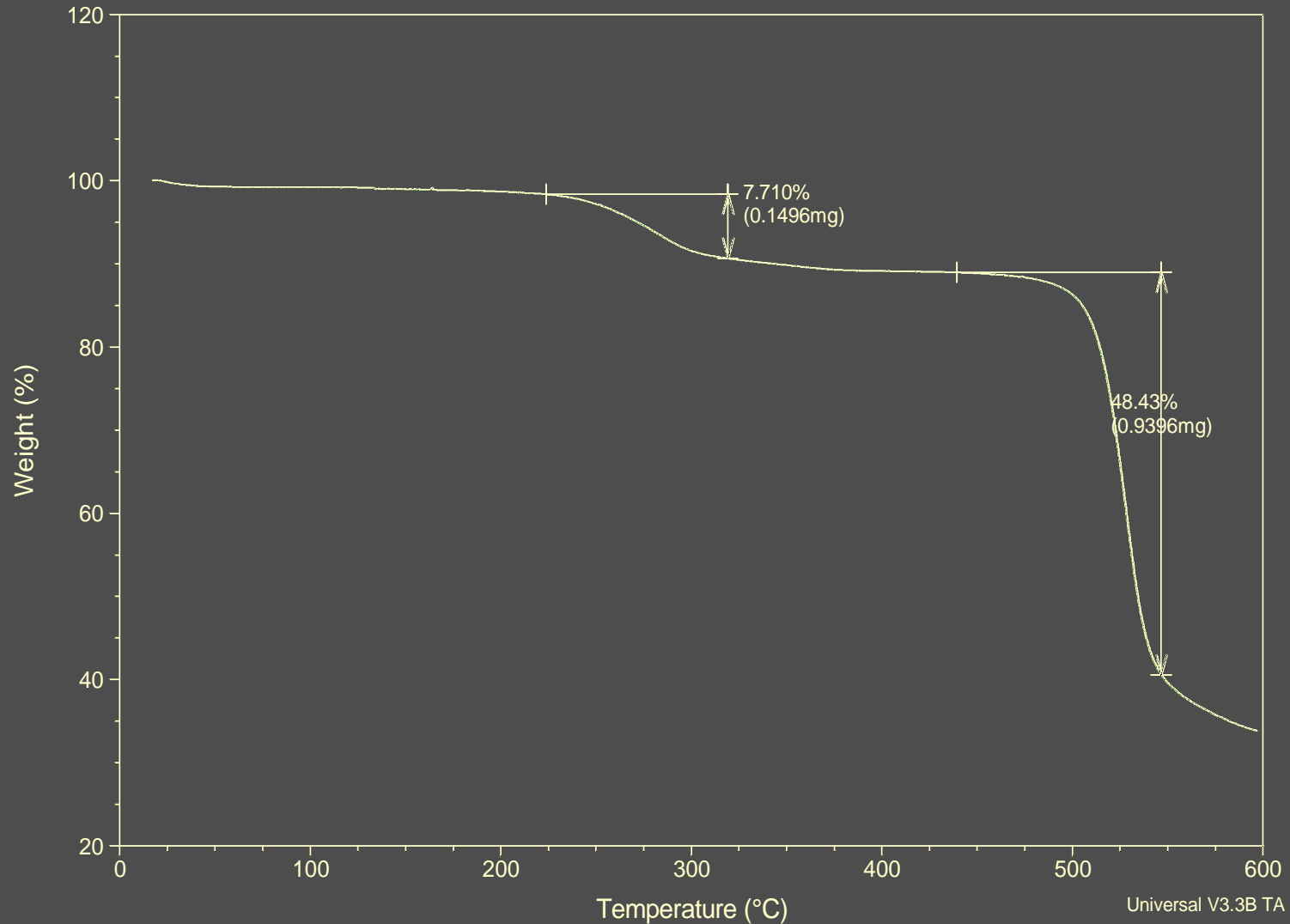


TGA-11% NCC

Sample: sample1_dec 30_tga
Size: 1.9400 mg
Method: Ramp

TGA

File: C:\Data\sweda\sample1_dec30_tga.001
Operator: sweda
Run Date: 30-Dec-04 10:41
Instrument: 2950 TGA HR V6.0E

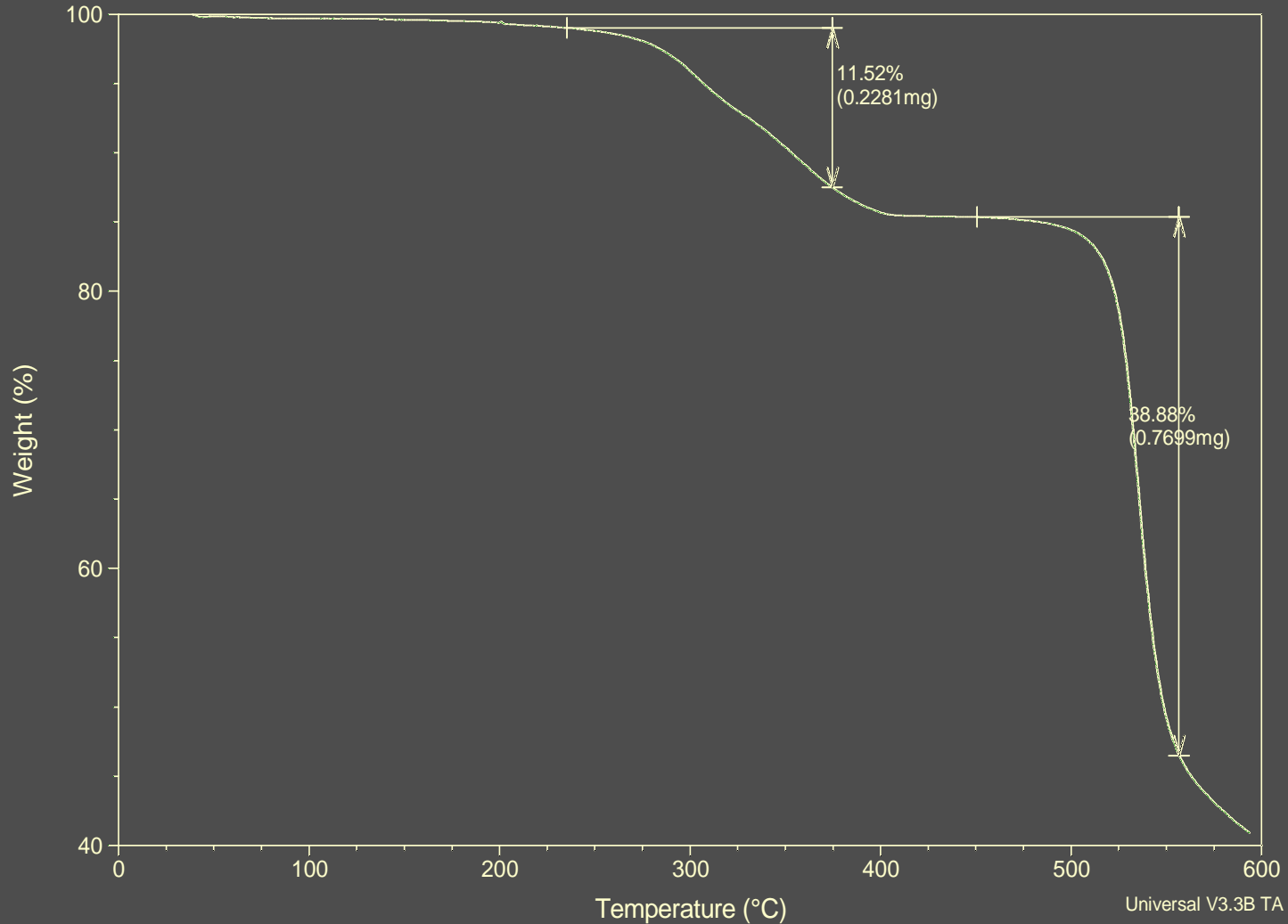


TGA-16% NCC

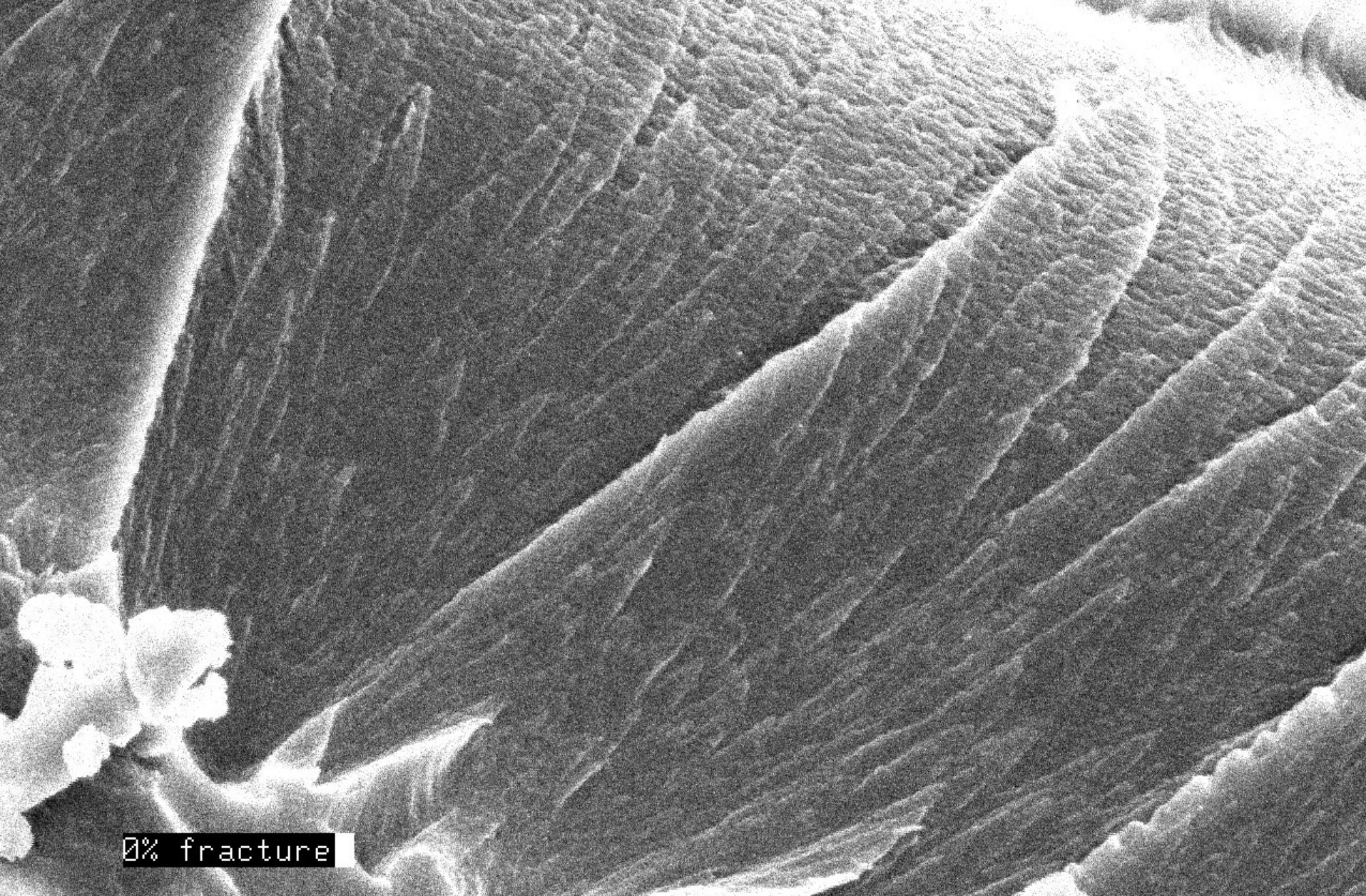
Sample: sample2_dec30_tga
Size: 1.9800 mg
Method: Ramp

TGA

File: C:\Data\sweda\sample2_dec30_tga.001
Operator: sweda
Run Date: 30-Dec-04 12:02
Instrument: 2950 TGA HR V6.0E



SEM



0% fracture

D: 14,000x

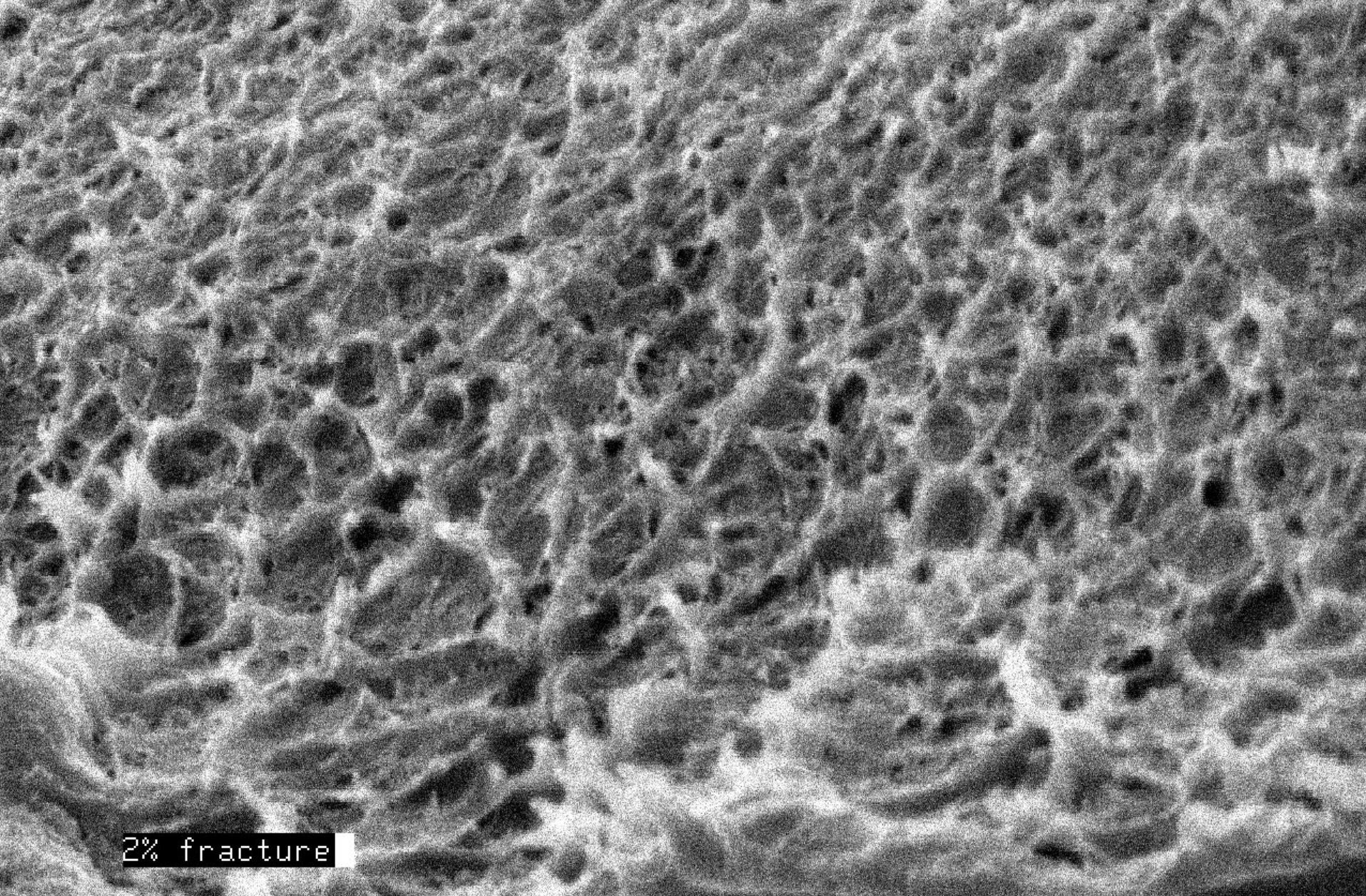
P: 5,000x

7.00 kV

1 μ m

AmRay@OSUEMF

#0001*



2% fracture

D: 19,600x

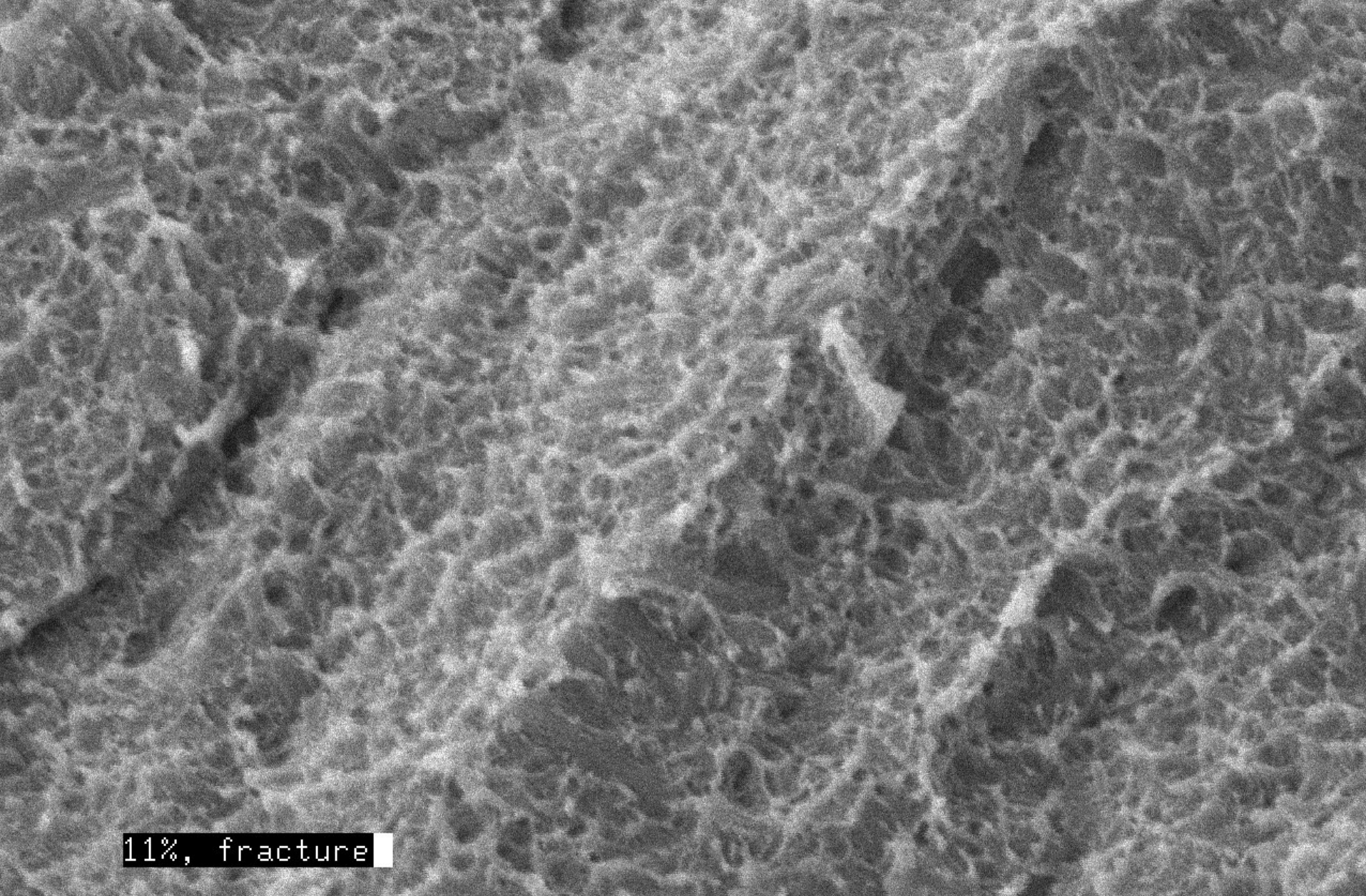
P: 7,000x

7.00 kV

1 μ m

AmRay@OSUEMF

#0001*



11%, fracture

D: 20,400x

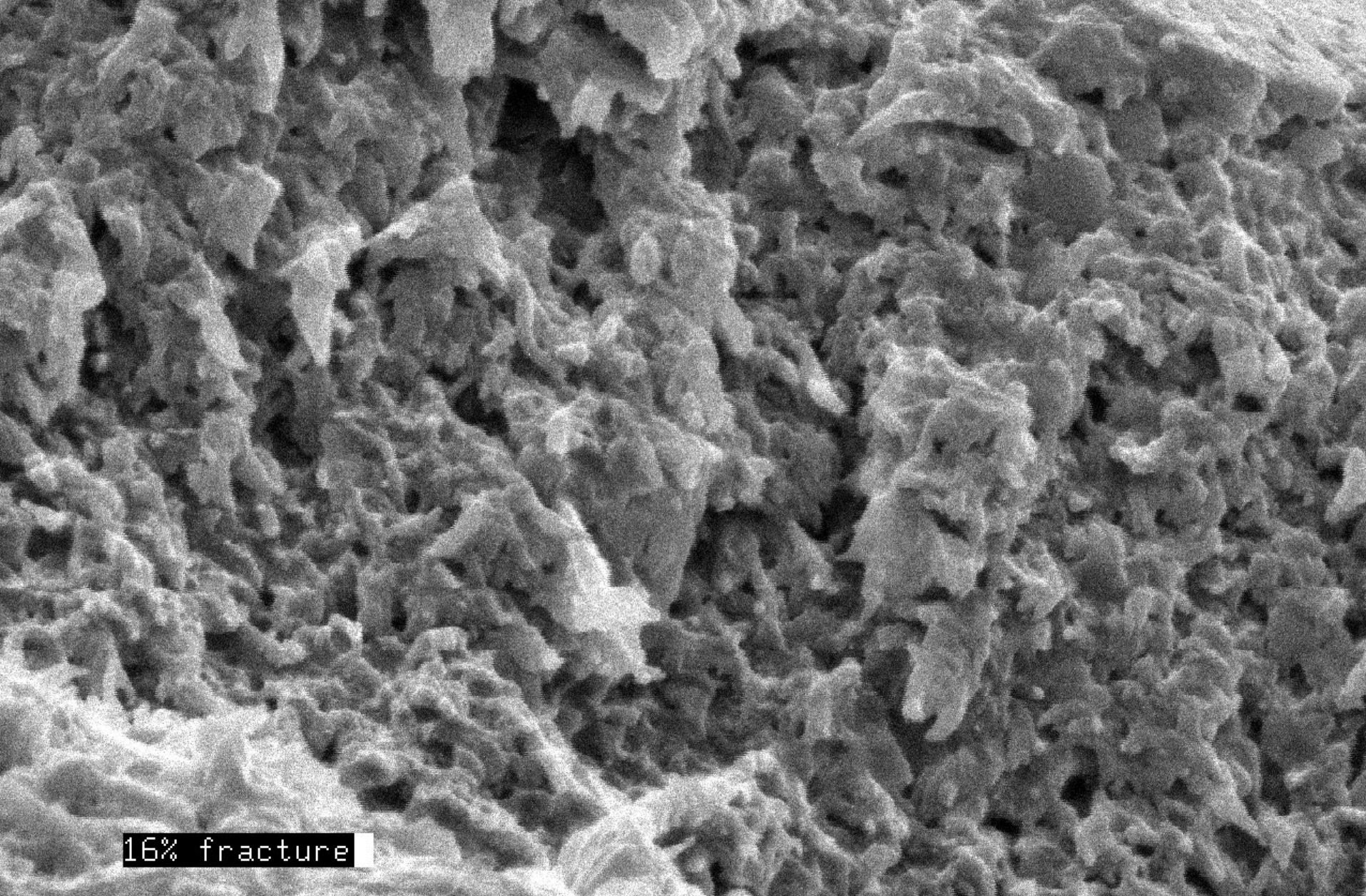
P: 7,300x

7.00 kV

1 μ m

AmRay@OSUEMF

#0001*



16% fracture

D: 21,000x

P: 7,500x

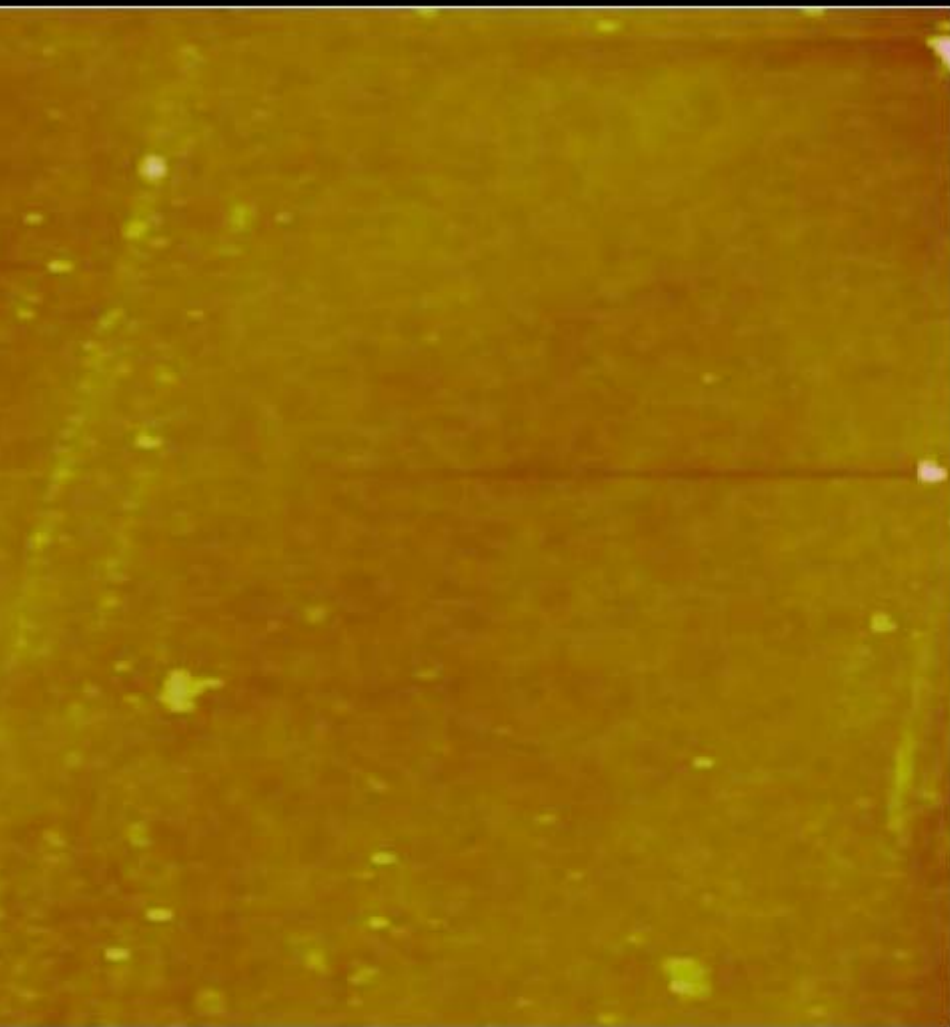
7.00 kV

1 μ m

AmRay@OSUEMF

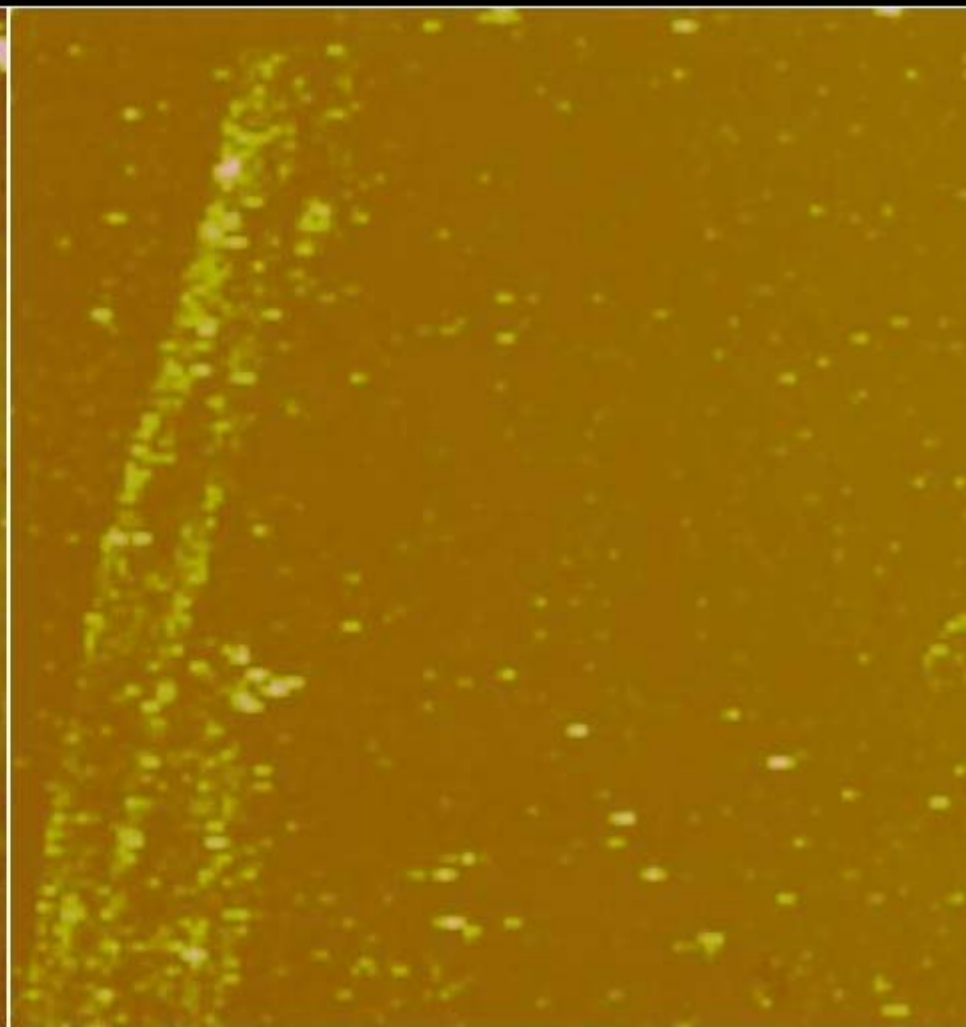
#0001*

AFM images



10.0 μm 0

Data type Height
Z range 20.00 nm

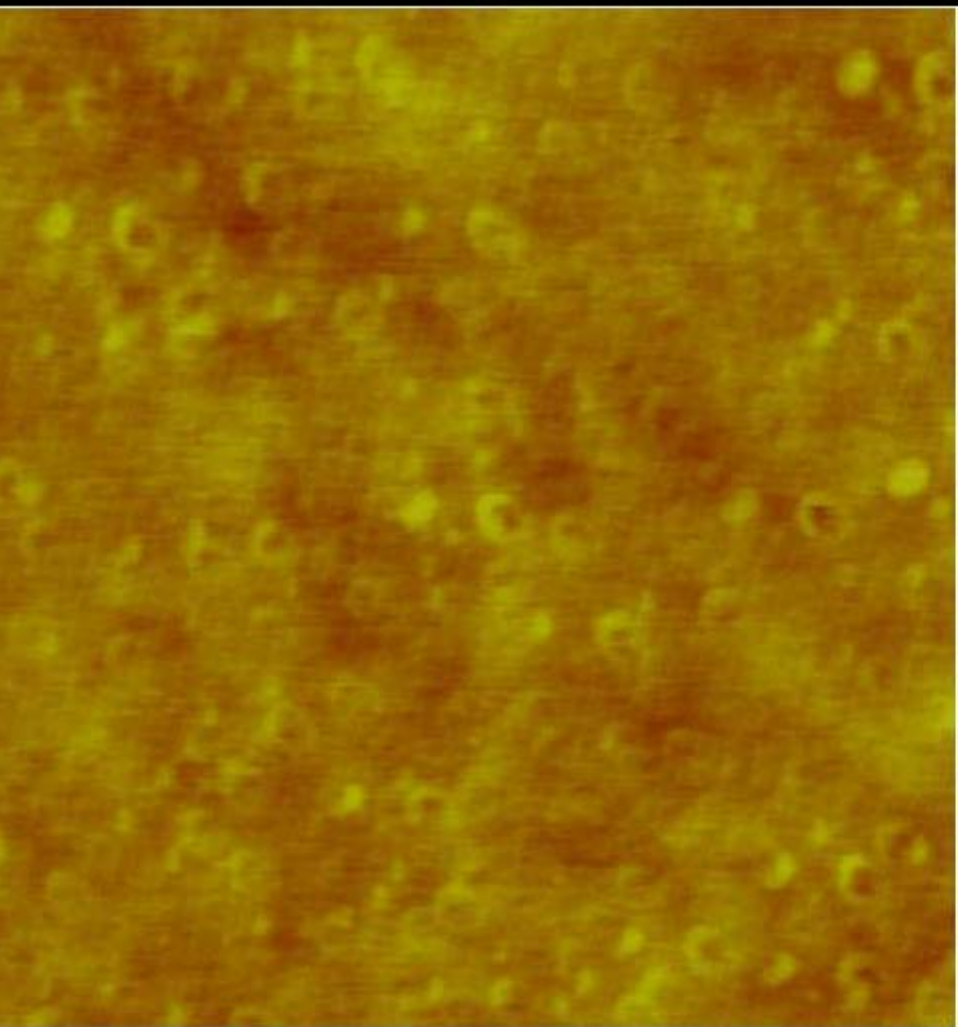


10.0

Data type Phase
Z range 150.0 $^{\circ}$

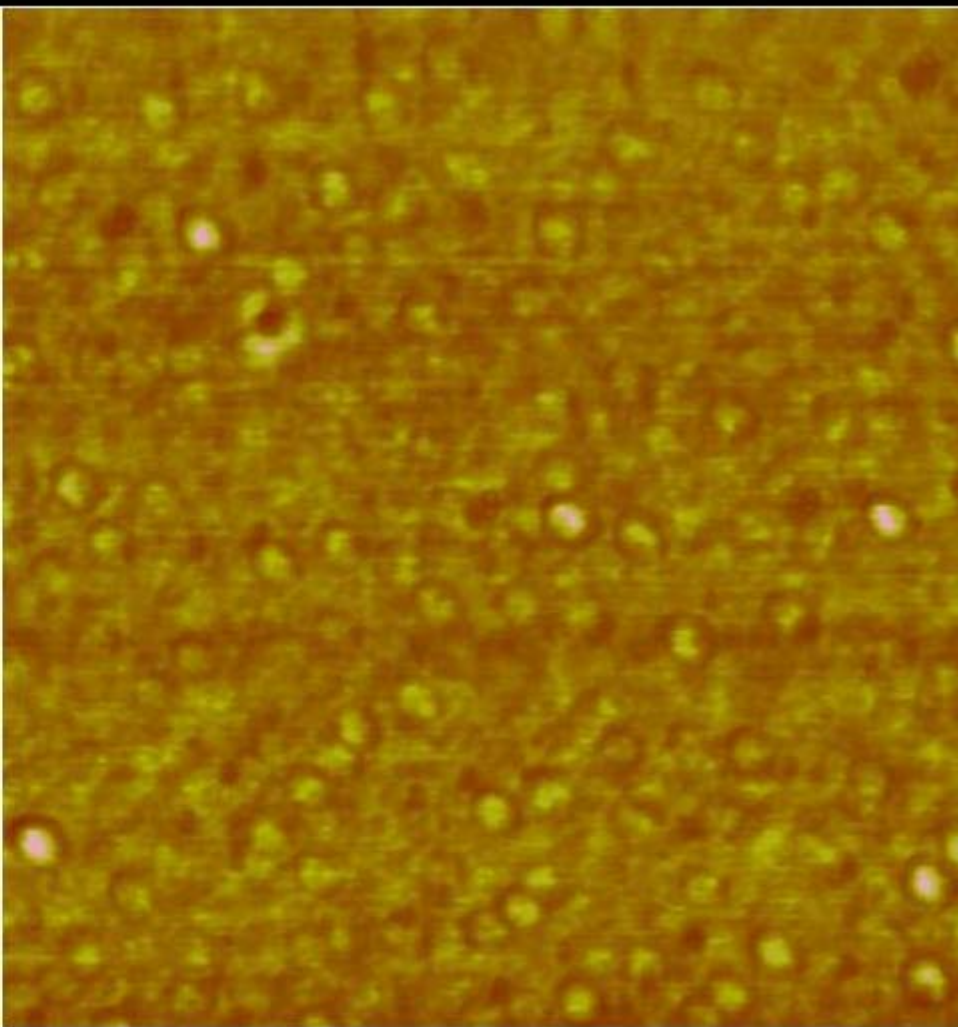
sf10micron2.000
/05 0% NCC in PSf second location

0% NCC



Data type Height
Z range 5.000 nm

1.00 μm 0



Data type Phase
Z range 70.00 °

1.00

sf1micron2.001
/05 0% NCC in PSf second location

0% NCC

Roughness Analysis

$R_{ms} = 0.184 \text{ nm}$

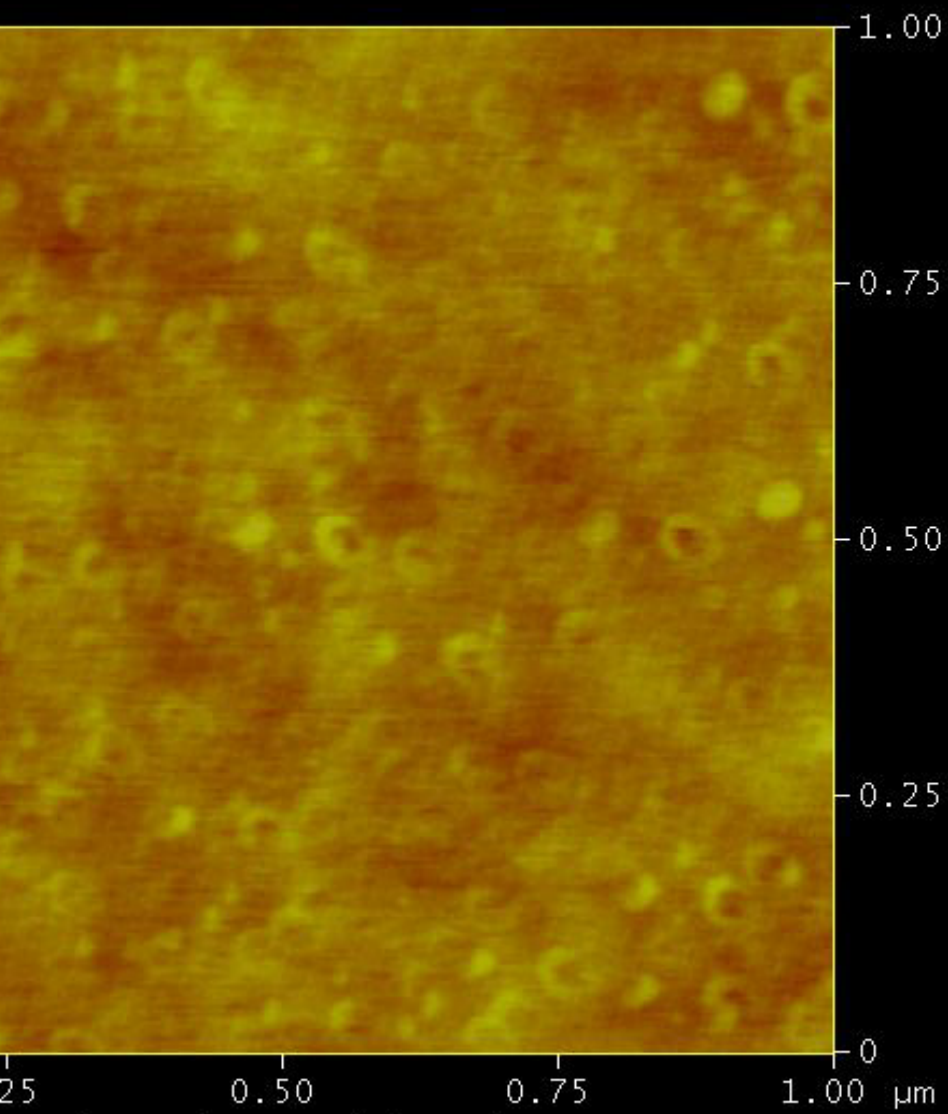


Image Statistics

Img. Z range	1.733 nm
Img. Mean	-0.000000 nm
Img. Raw mean	-1.325 μm
Img. Rms (Rq)	0.184 nm
Img. Ra	0.143 nm
Img. Rmax	1.733 nm
Img. Srf. area	1.001 μm ²
Img. Prj. Srf. area	999999 nm ²
Img. Srf. area diff	0.059 %
Img. SAE	1.000

Box Statistics

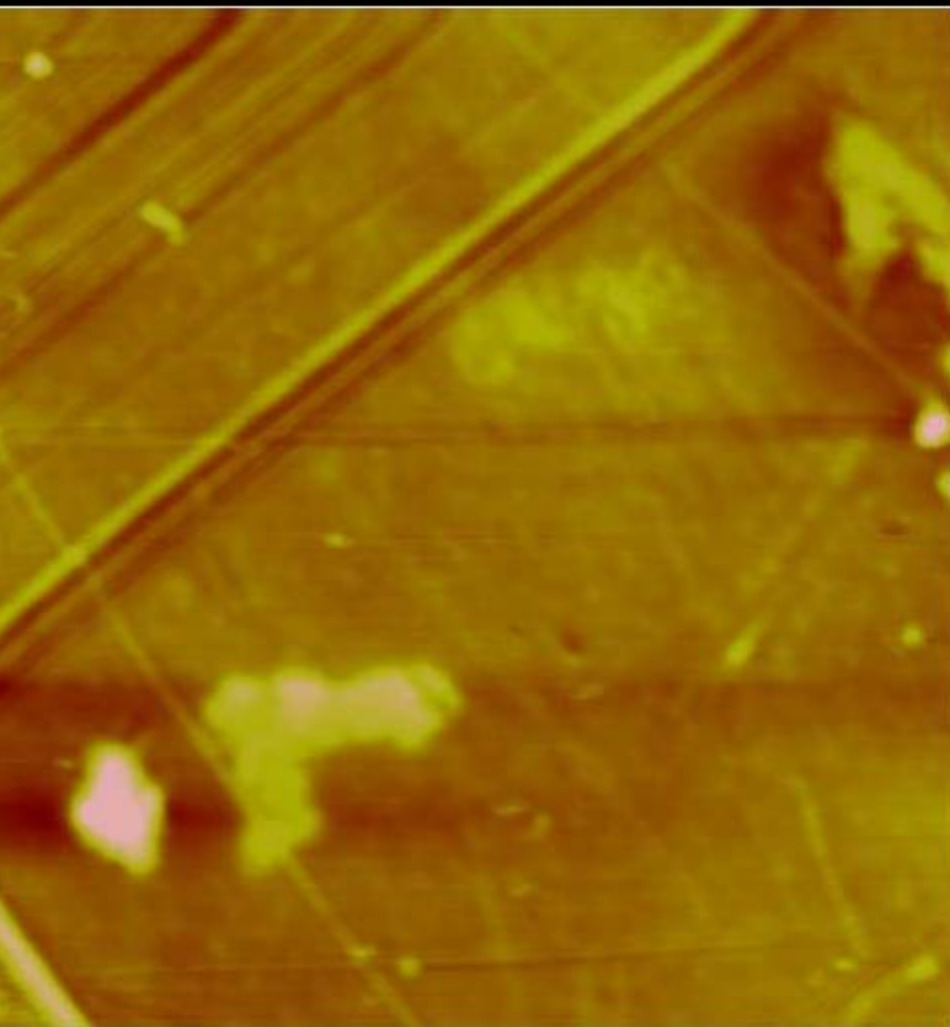
Z range	
Mean	
Raw mean	
Rms (Rq)	
Mean roughness (Ra)	
Max height (Rmax)	

0% NCC

Summit Off

Zero Cross. Off

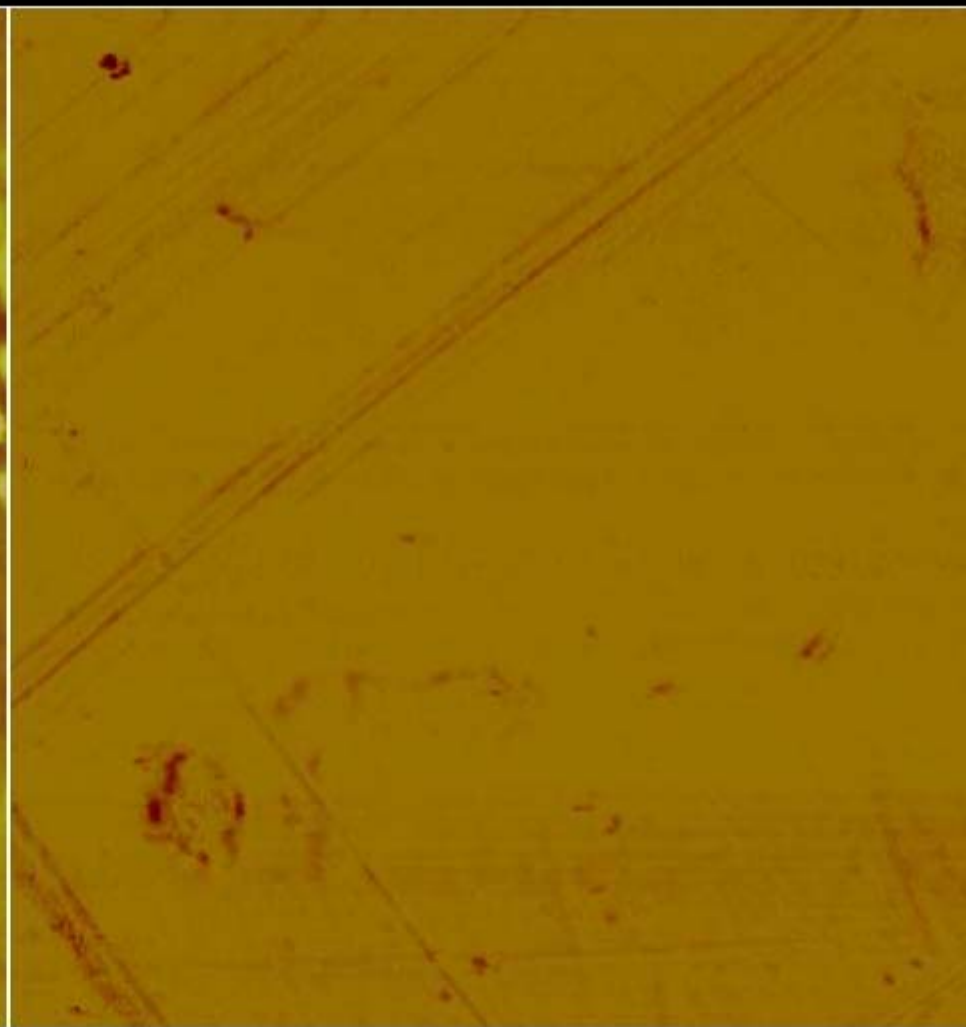
Box Cursor



Data type
Z range

Height
50.00 nm

10.0 μm 0



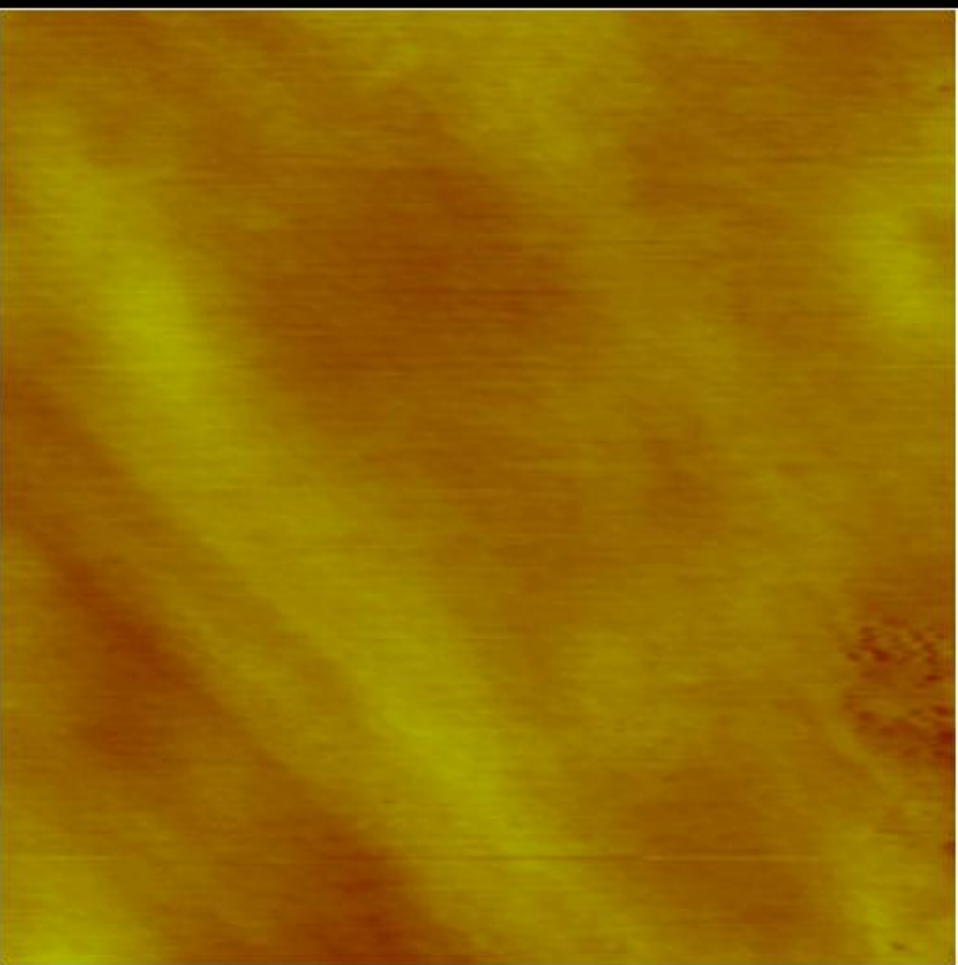
Data type
Z range

Phase
10.00 $^{\circ}$

10.0

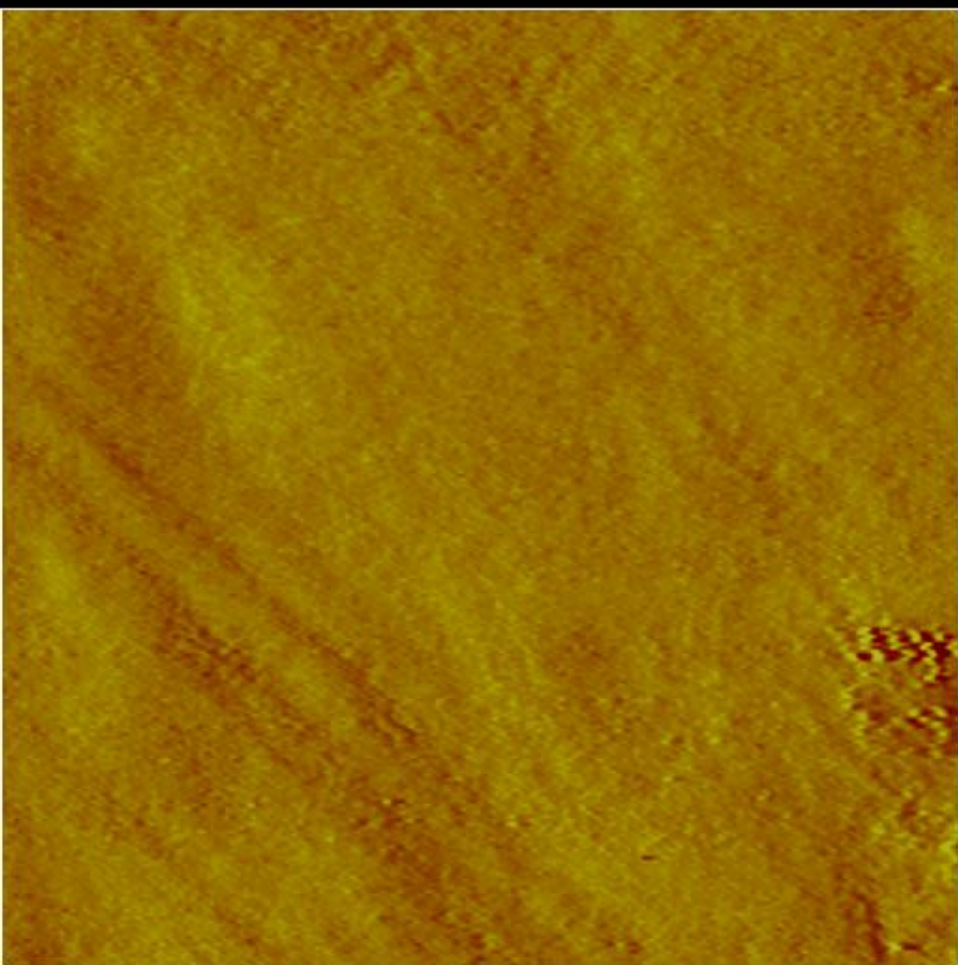
s f10micron.000

2% NCC



0 1.00 μm 0

Data type Height
Z range 10.000 nm

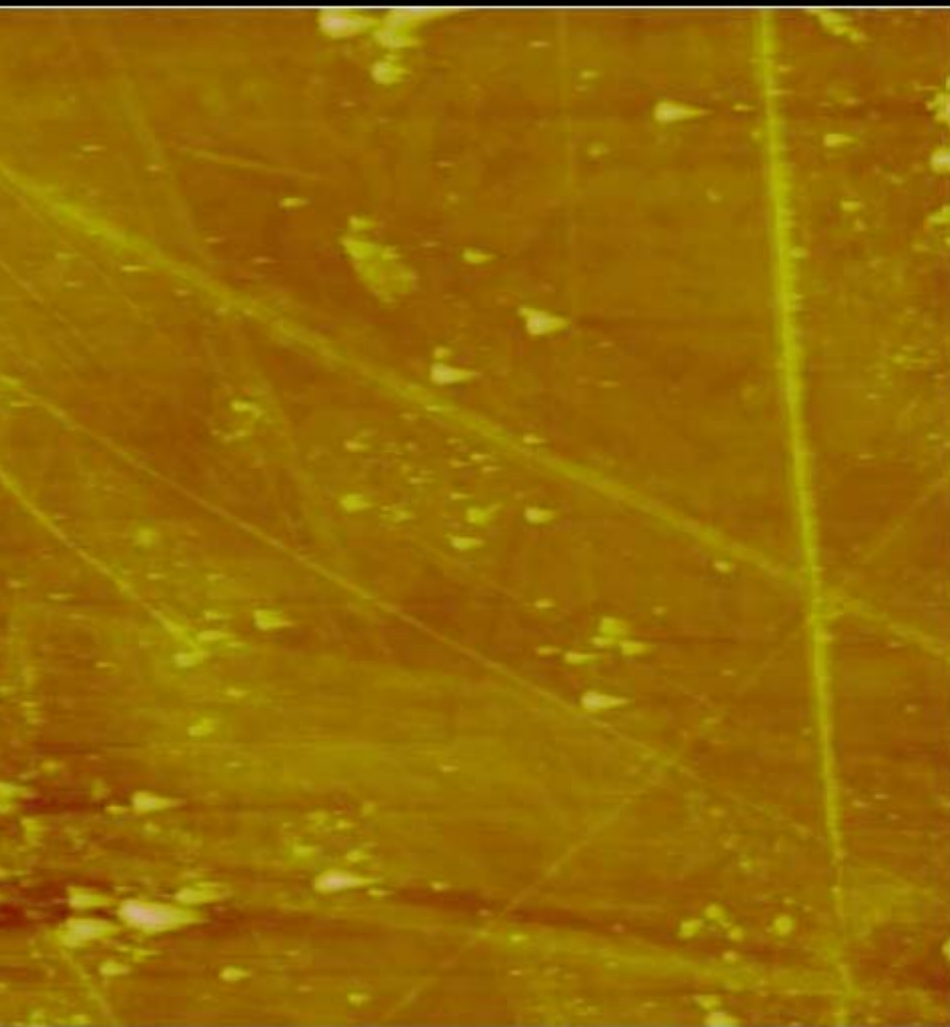


0 1.00 μm 0

Data type Phase
Z range 20.00 °

2%psf1micron.001
3/9/05 2% NCC in PSf, film

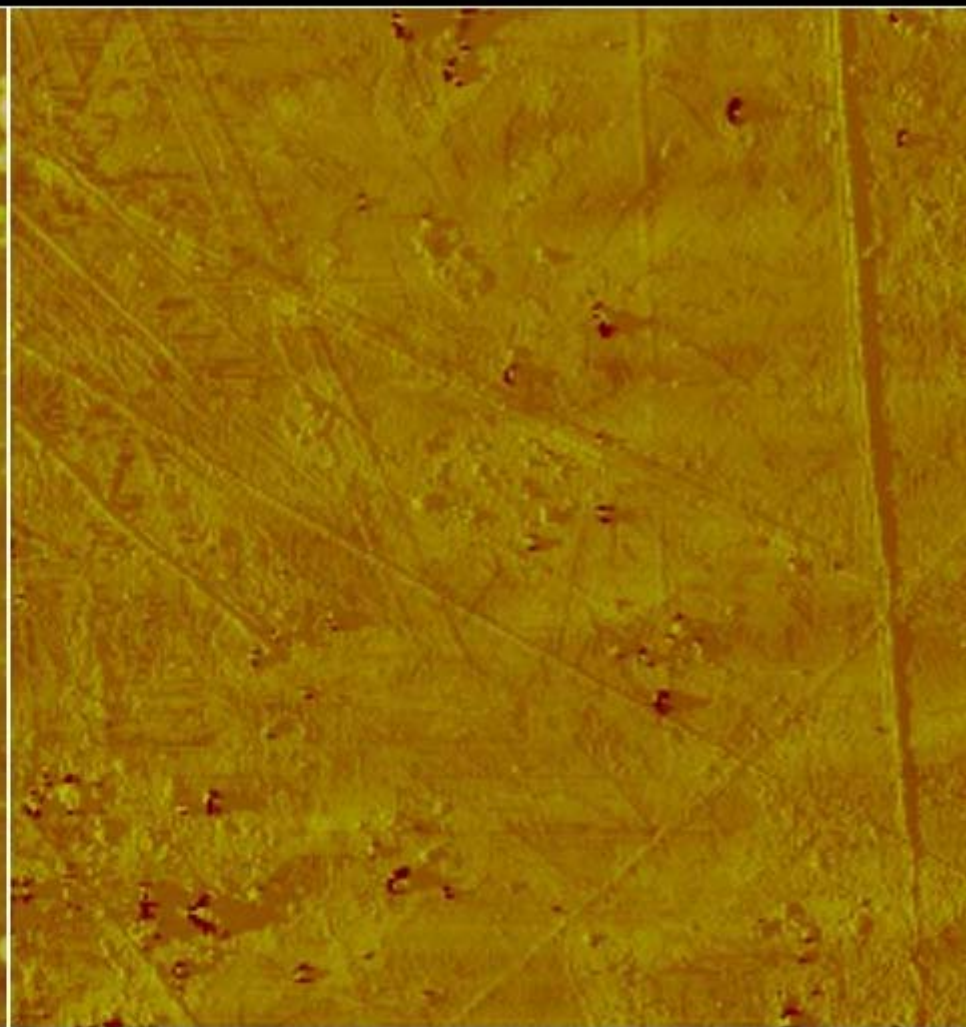
2% NCC



Data type
Z range

Height
200.0 nm

20.0 μm



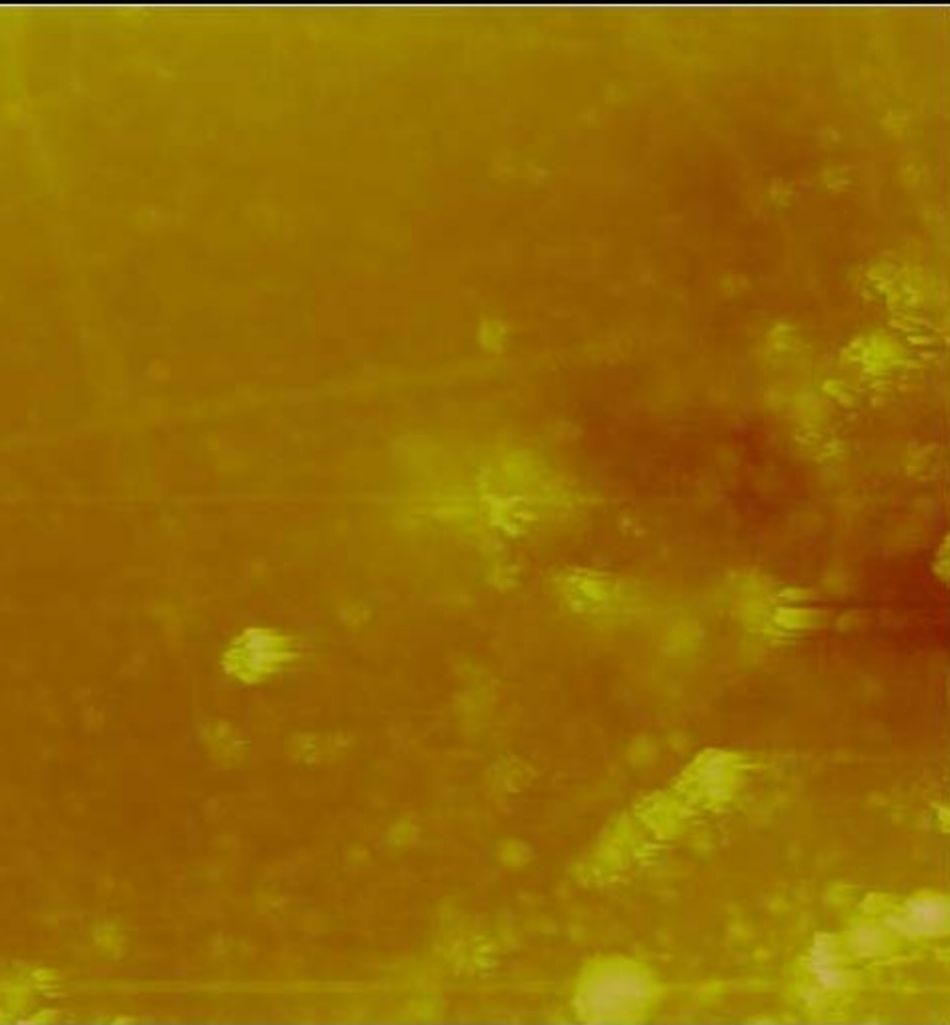
Data type
Z range

Phase
120.0 °

20.0

osf20micron.001
/05

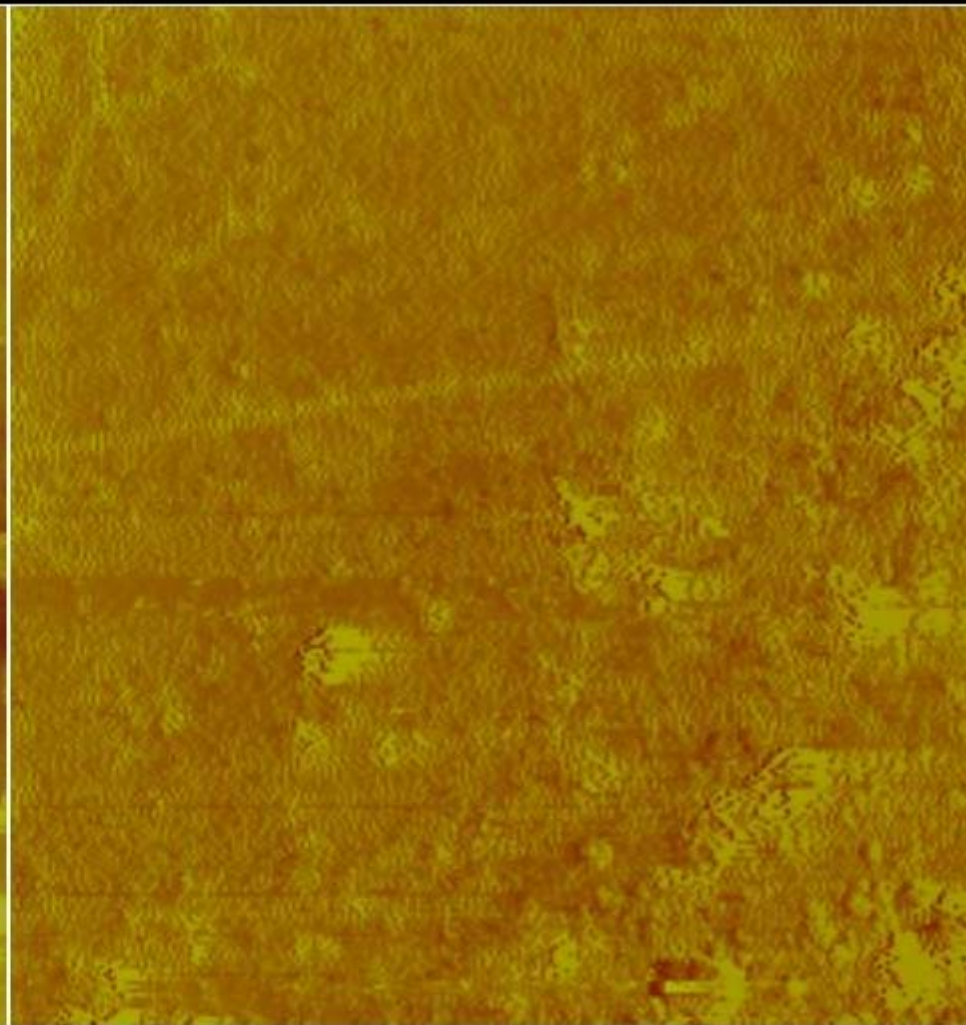
11% NCC



10.0 μm 0

Data type
Z range

Height
300.0 nm



10.0

Data type
Z range

Phase
150.0 $^{\circ}$

osf10micron.001
/05

11% NCC

Roughness Analysis

$R_{ms} = 13 \text{ nm}$

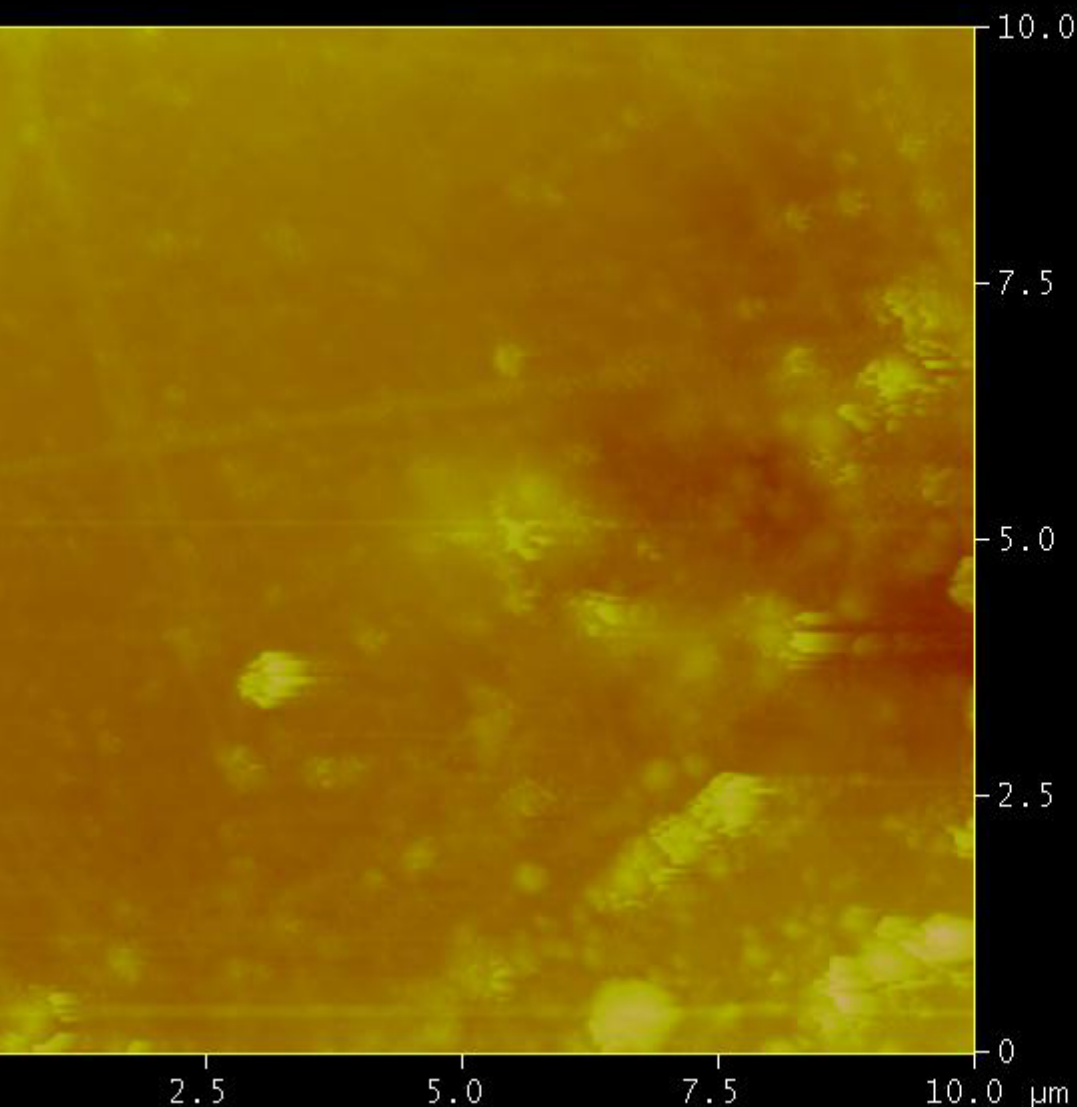


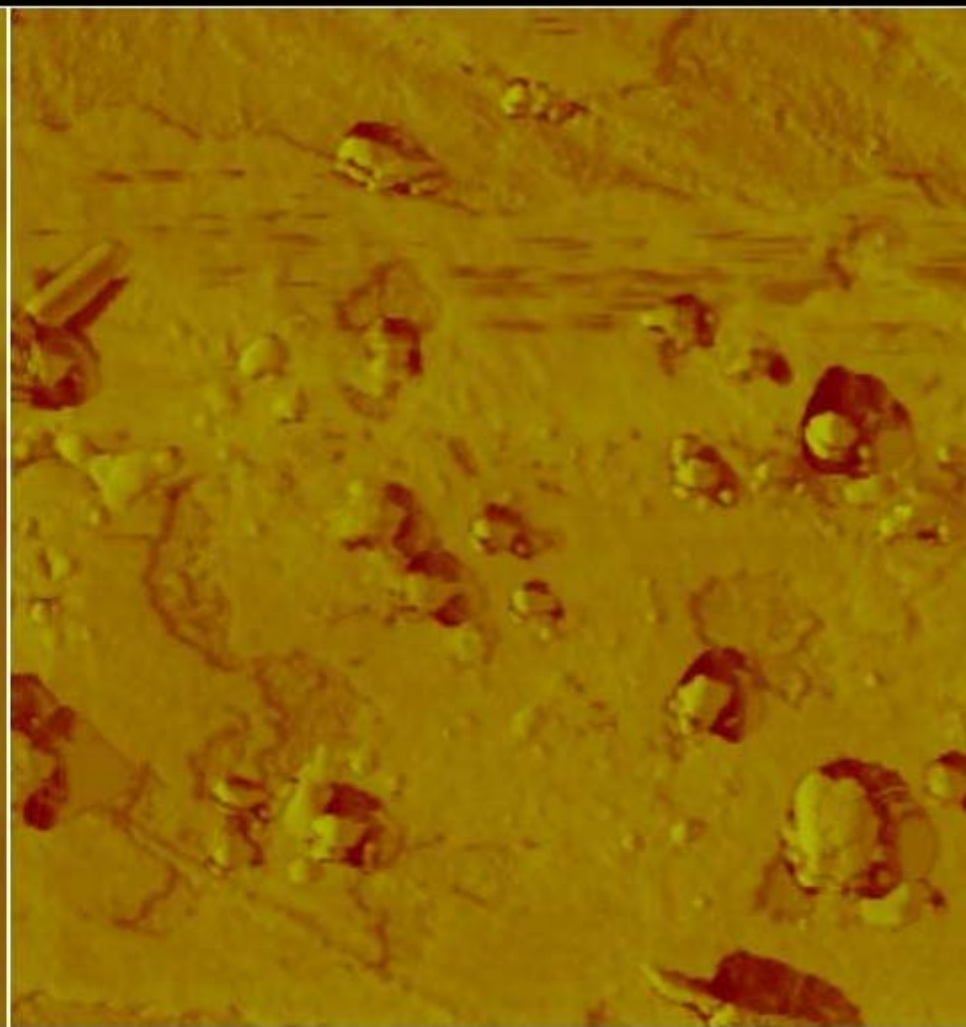
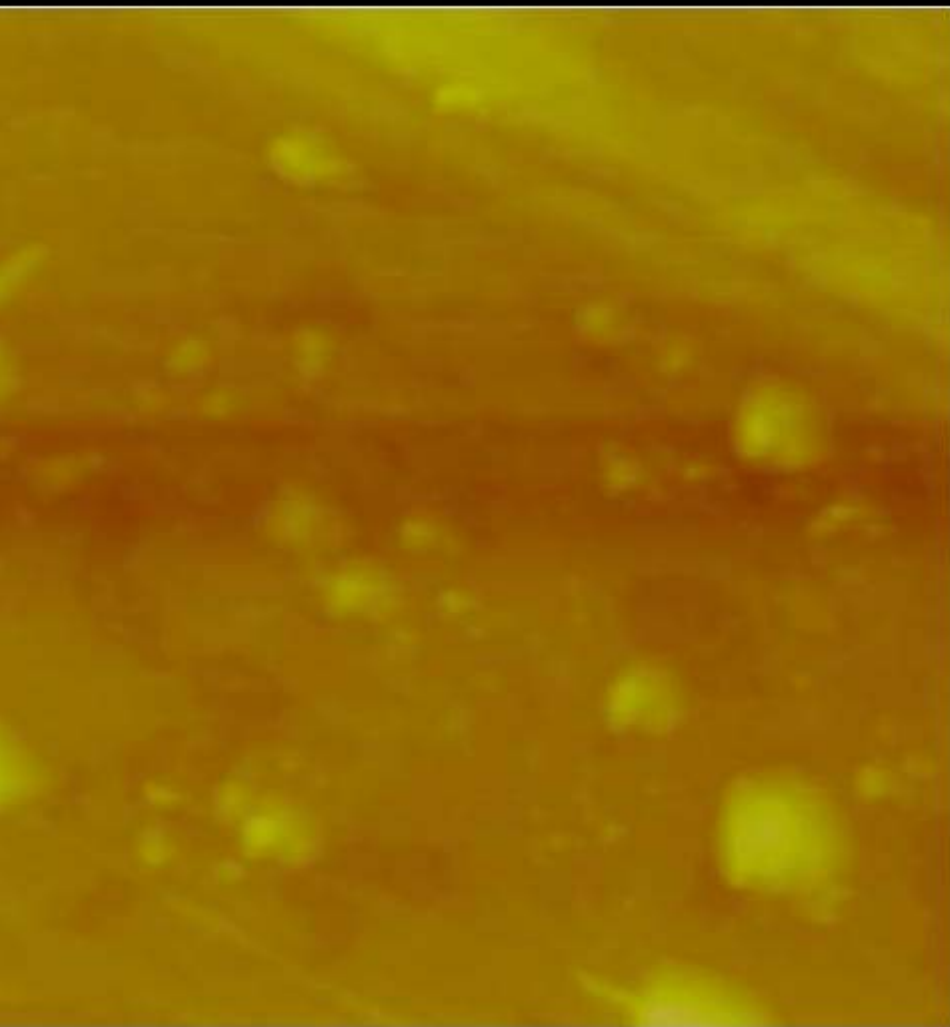
Image Statistics

Img. Z range	143.08 nm
Img. Mean	0.039 nm
Img. Raw mean	-464.60 nm
Img. Rms (Rq)	12.641 nm
Img. Ra	8.876 nm
Img. Rmax	142.41 nm
Img. Srf. area	100.91 μm^2
Img. Prj. Srf. area	100.00 μm^2
Img. Srf. area diff	0.915 %
Img. SAE	1.003

Box Statistics

Z range
Mean
Raw mean
Rms (Rq)
Mean roughness (Ra)
Max height (Rmax)

11% NCC



3.00 μm 0

3.00

Data type
Z range

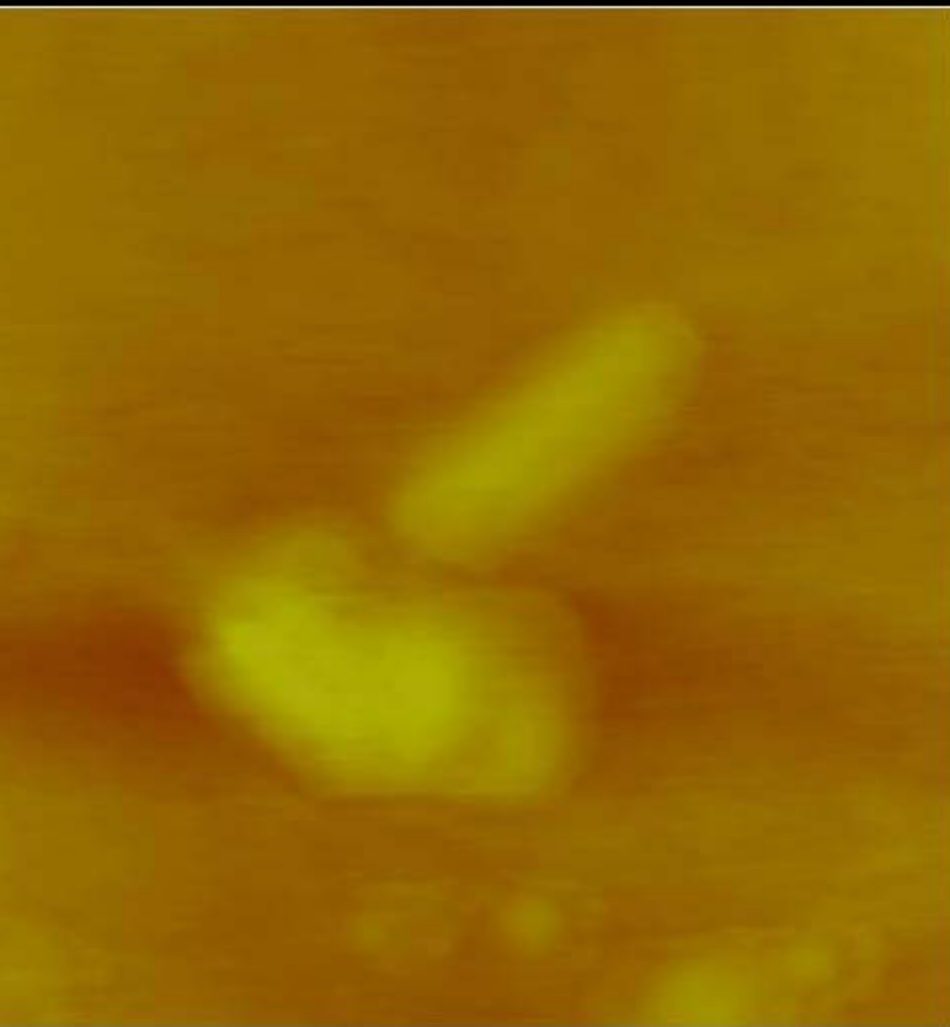
Height
200.0 nm

Data type
Z range

Phase
150.0 $^{\circ}$

osf3micron.001
/05

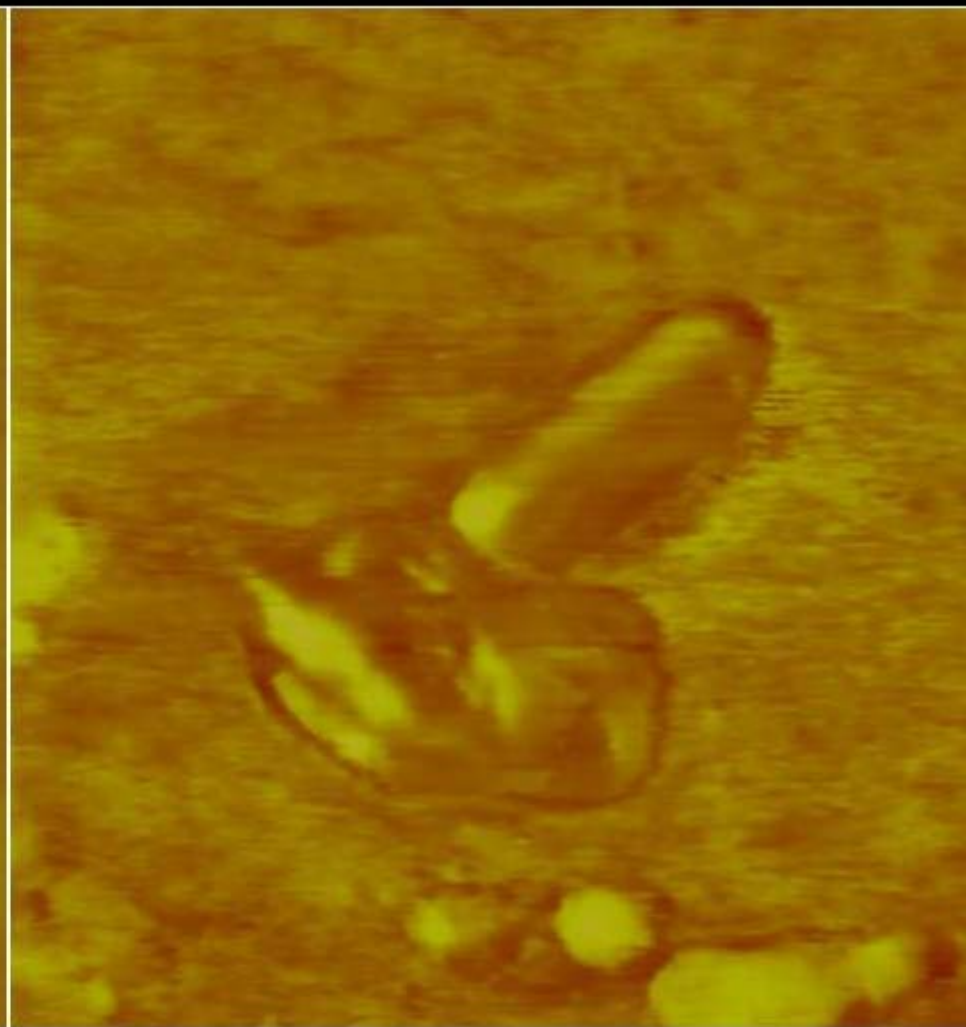
11% NCC



Data type
Z range

Height
50.00 nm

1.00 μm 0



Data type
Z range

Phase
180.0 $^{\circ}$

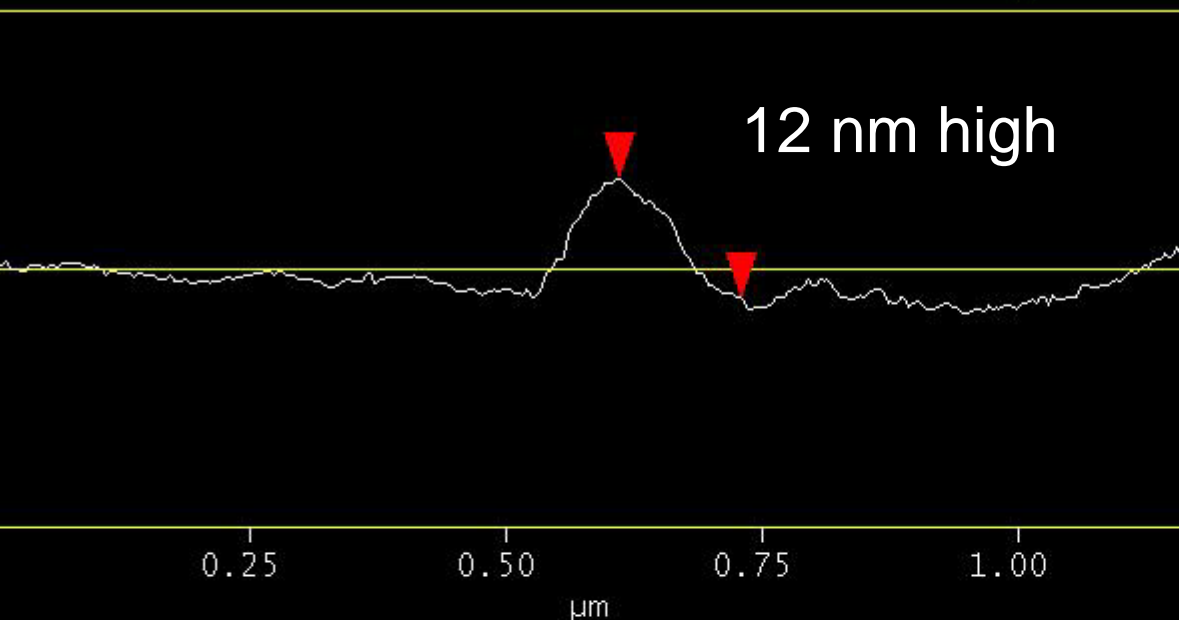
1.00

osf1micron.003
/05 0.8 setpt

11% NCC

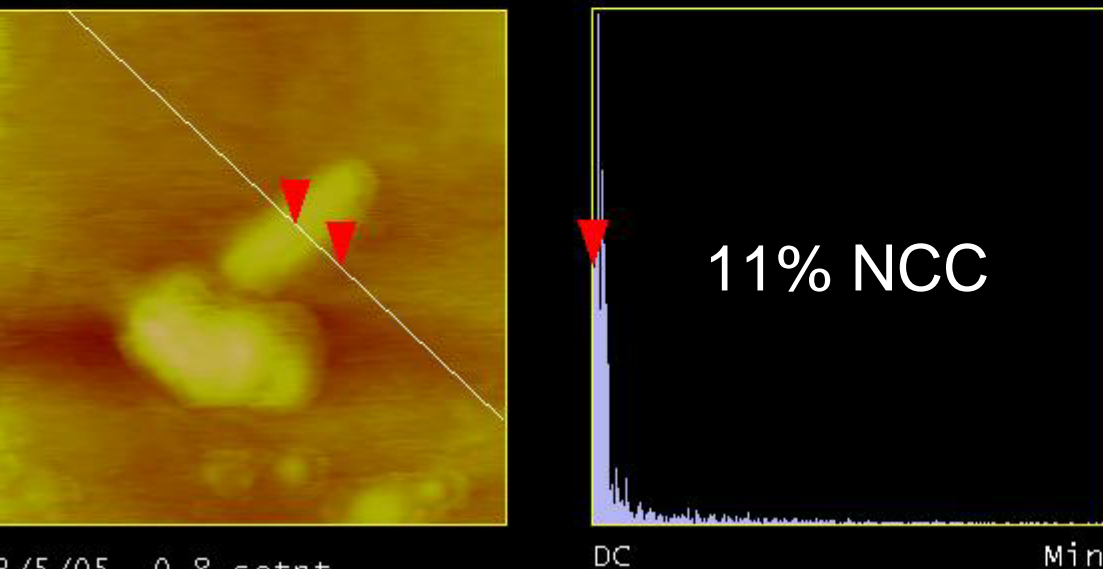
nm

Section Analysis



L	121.09 nm
RMS	4.070 nm
lc	DC
Ra(lc)	0.616 nm
Rmax	2.426 nm
Rz	1.447 nm
Rz Cnt	6
Radius	169.04 nm
Sigma	3.435 nm

Spectrum

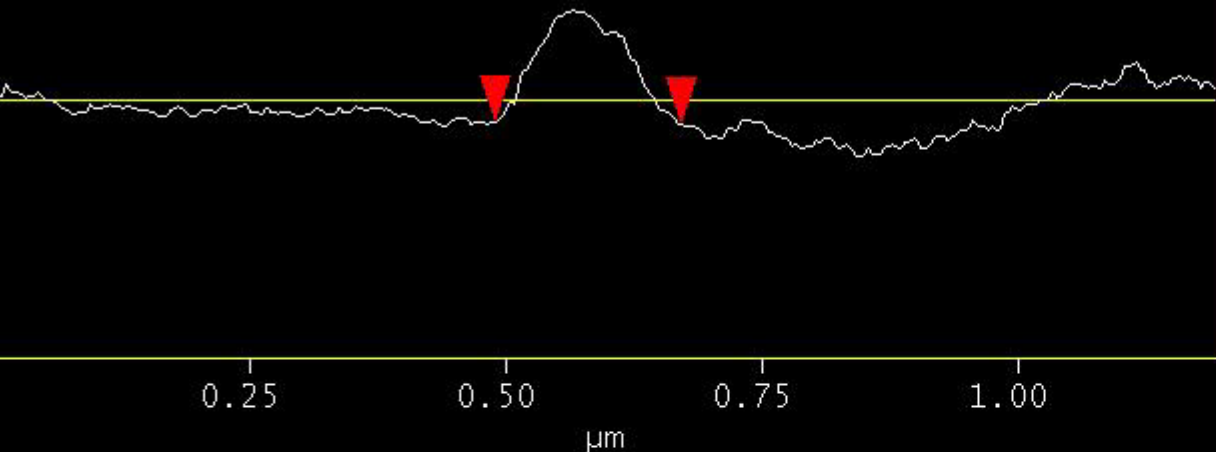


Surface distance	122.16 nm
Horiz distance(L)	121.09 nm
Vert distance	12.077 nm
Angle	5.695 °
Surface distance	
Horiz distance	
Vert distance	
Angle	
Surface distance	
Horiz distance	
Vert distance	
Angle	
Spectral period	DC
Spectral freq	0 Hz
Spectral RMS amp	0.002 nm

nm

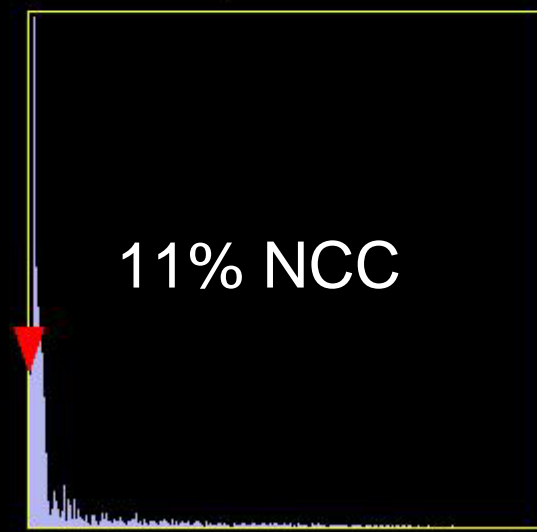
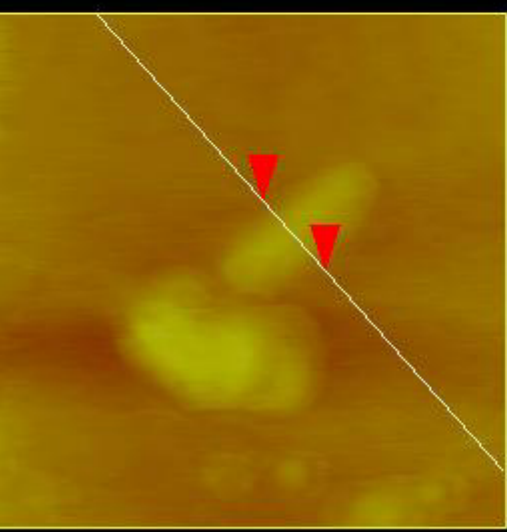
Section Analysis

184 nm wide



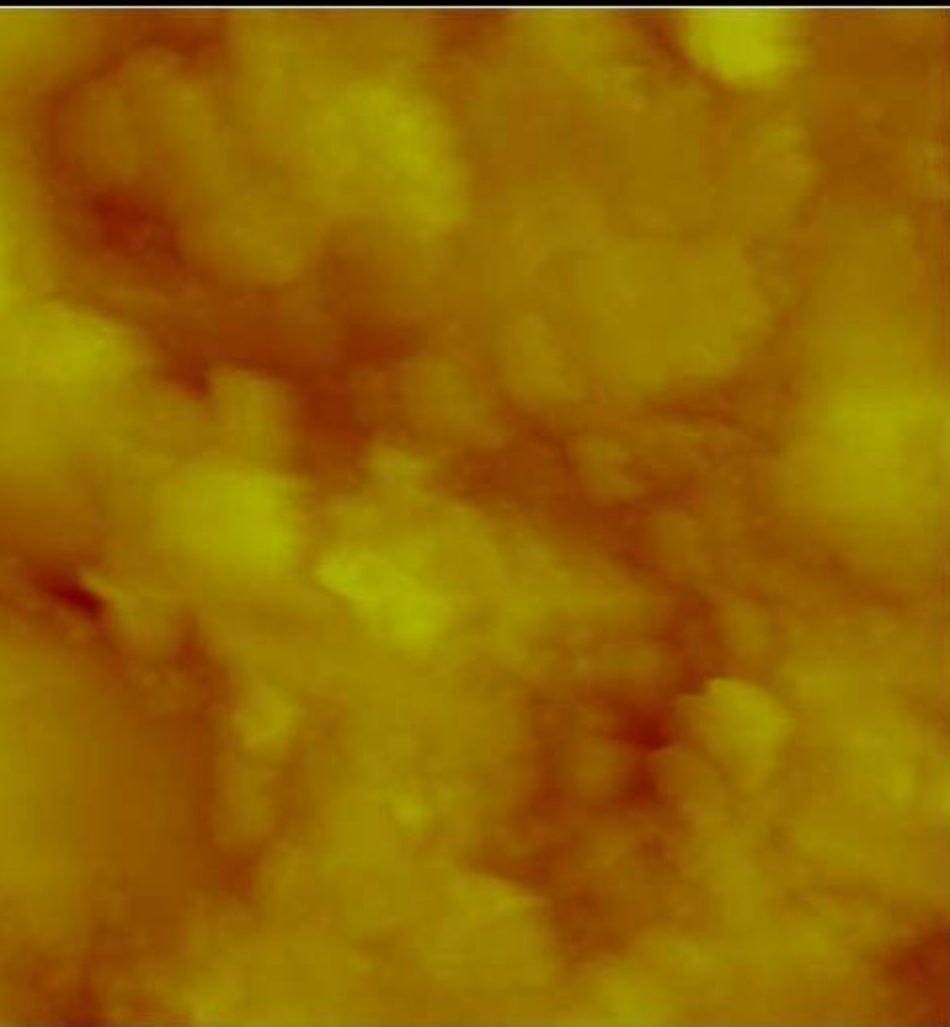
L	183.59 nm
RMS	3.837 nm
lc	DC
Ra(lc)	3.316 nm
Rmax	11.890 nm
Rz	11.890 nm
Rz Cnt	2
Radius	340.64 nm
Sigma	0.987 nm

Spectrum



11% NCC

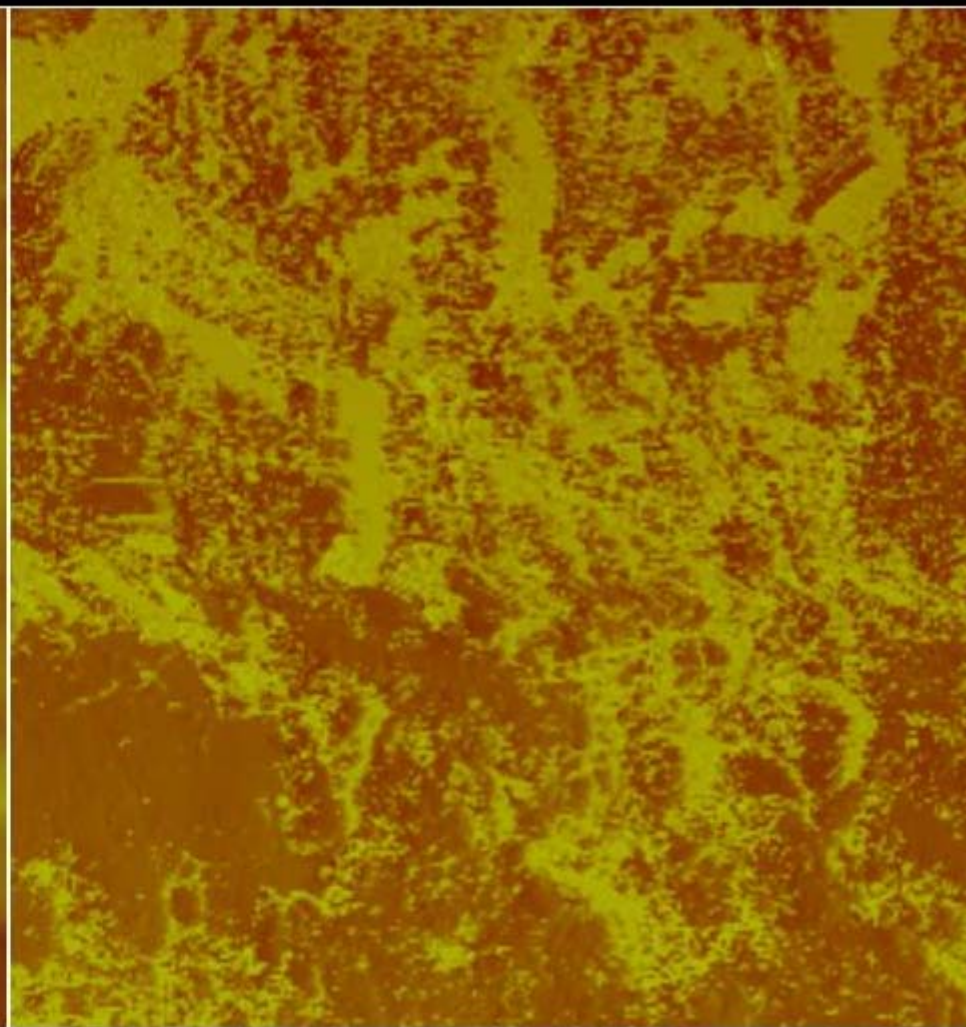
Surface distance	186.24 nm
Horiz distance(L)	183.59 nm
Vert distance	0.315 nm
Angle	0.098 °
Surface distance	
Horiz distance	
Vert distance	
Angle	
Surface distance	
Horiz distance	
Vert distance	
Angle	
Spectral period	DC
Spectral freq	0 Hz
Spectral RMS amp	0.001 nm



Data type
Z range

Height
1000 nm

10.0 μm 0



Data type
Z range

Phase
180.0 $^{\circ}$

10.0

psf10microndown.001
/05 11% NCC in PSF down sample

11% NCC, other side of film

Roughness Analysis

$R_{ms} = 96 \text{ nm}$

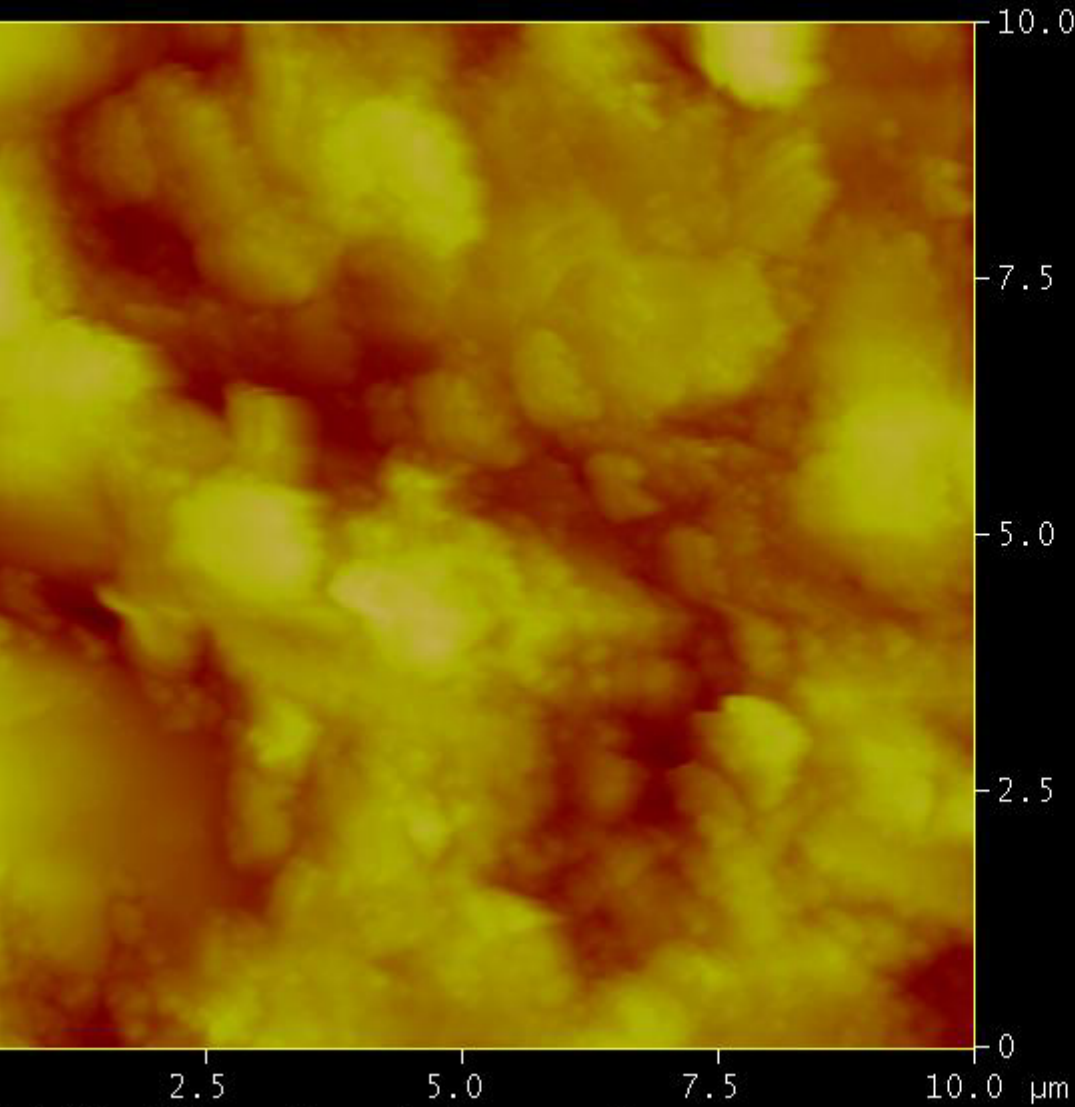
(other side = 13 nm)

Image Statistics

Img. Z range	705.35 nm
Img. Mean	-0.000001 nm
Img. Raw mean	12.462 nm
Img. Rms (Rq)	96.118 nm
Img. Ra	77.393 nm
Img. Rmax	705.35 nm
Img. Srf. area	108.23 μm^2
Img. Prj. Srf. area	100.00 μm^2
Img. Srf. area diff	8.230 %
Img. SAE	1.039

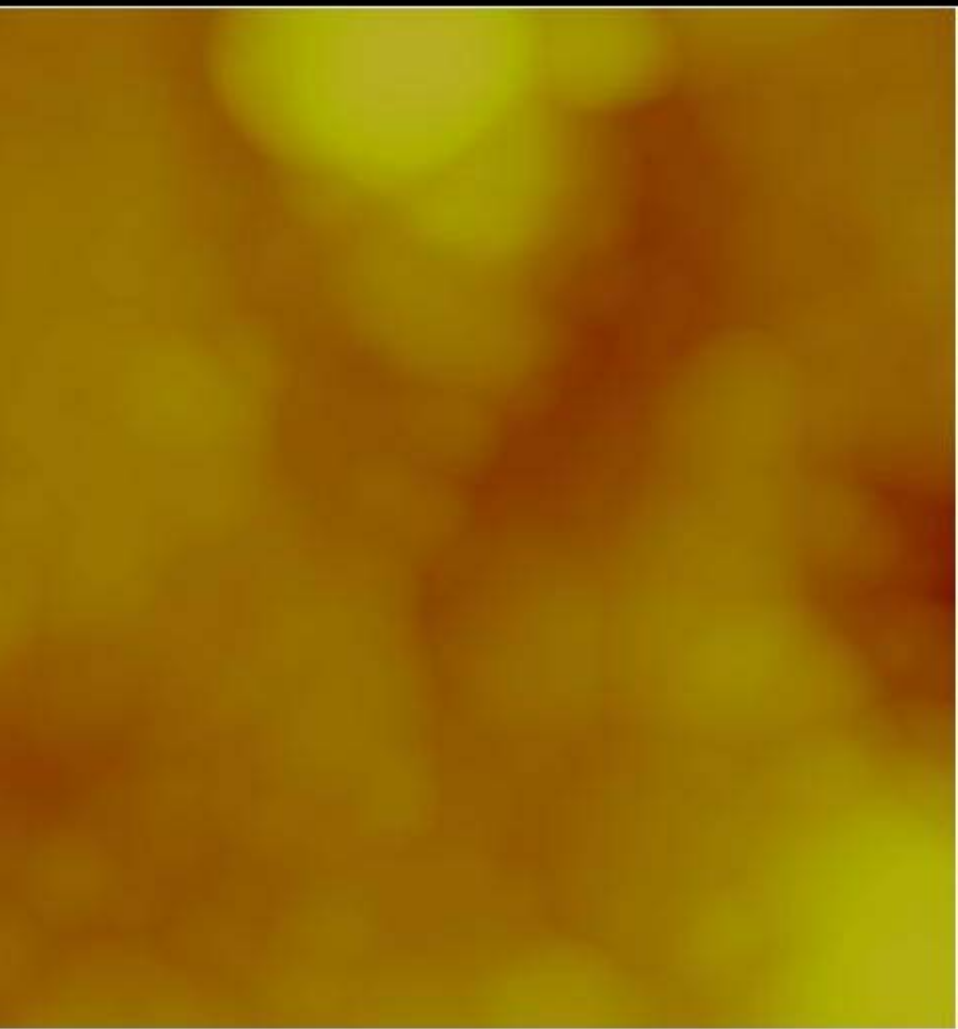
Box Statistics

Z range
Mean
Raw mean
Rms (Rq)
Mean roughness (Ra)
Max height (Rmax)



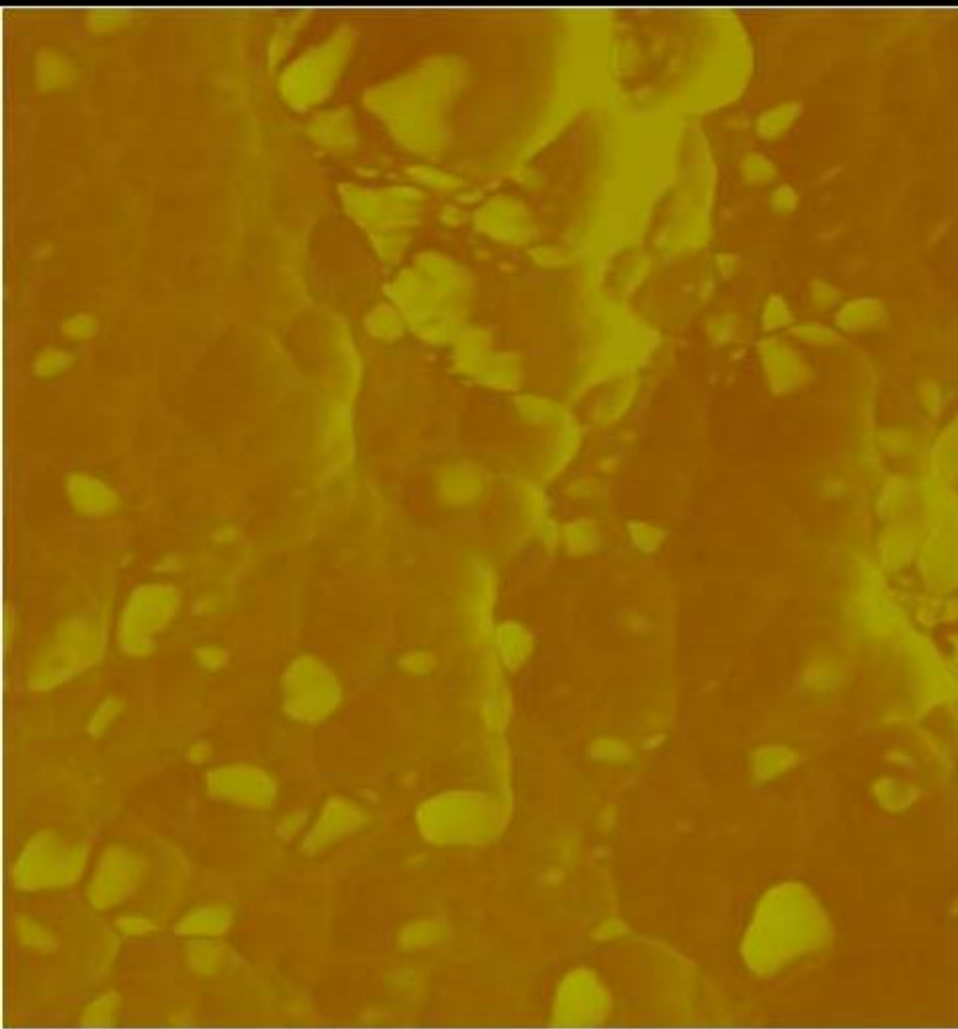
3/9/05 11% NCC in PSF down sample
%psf10microndown.001

11% NCC



1.00 μm 0

Data type Height
Z range 300.0 nm



1.00

Data type Phase
Z range 180.0 $^{\circ}$

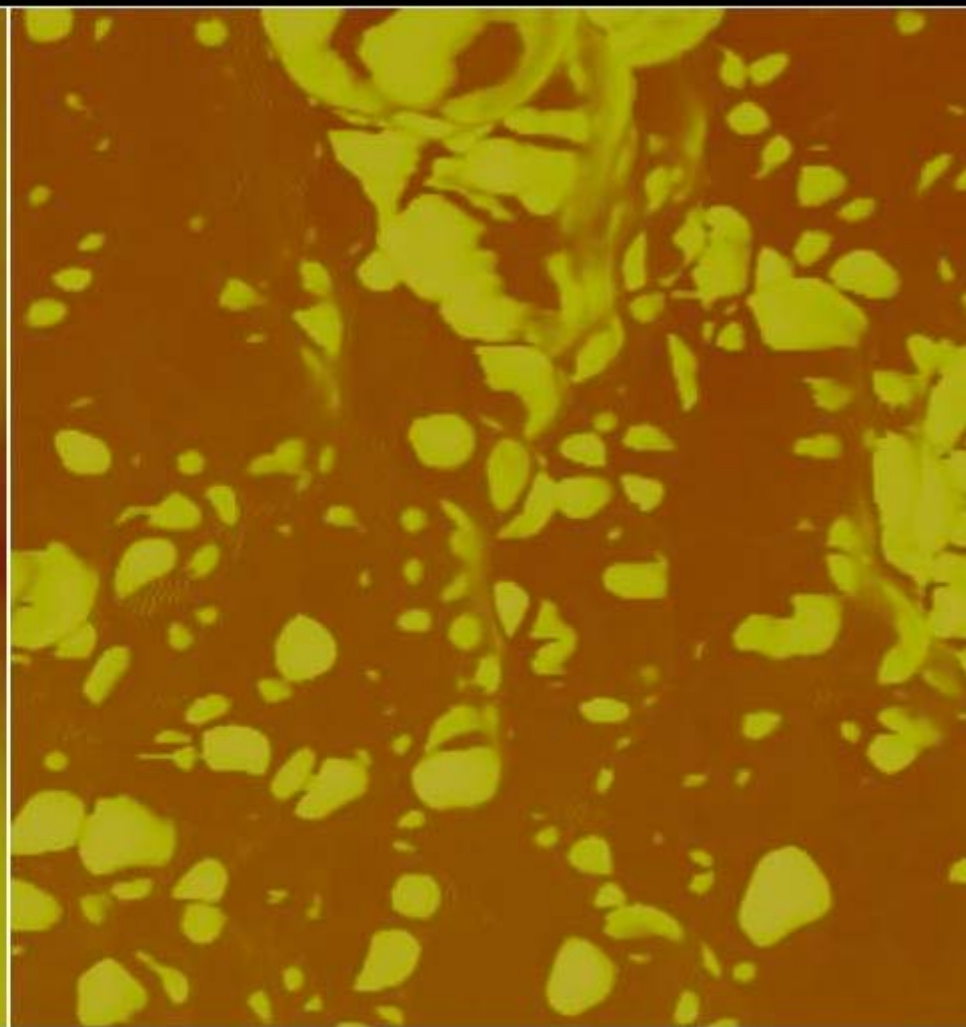
osf1microndownlt.002
/05 11% NCC in PSF down sample light tapping

11% NCC, light tapping



Data type Height
Z range 300.0 nm

1.00 μm 0

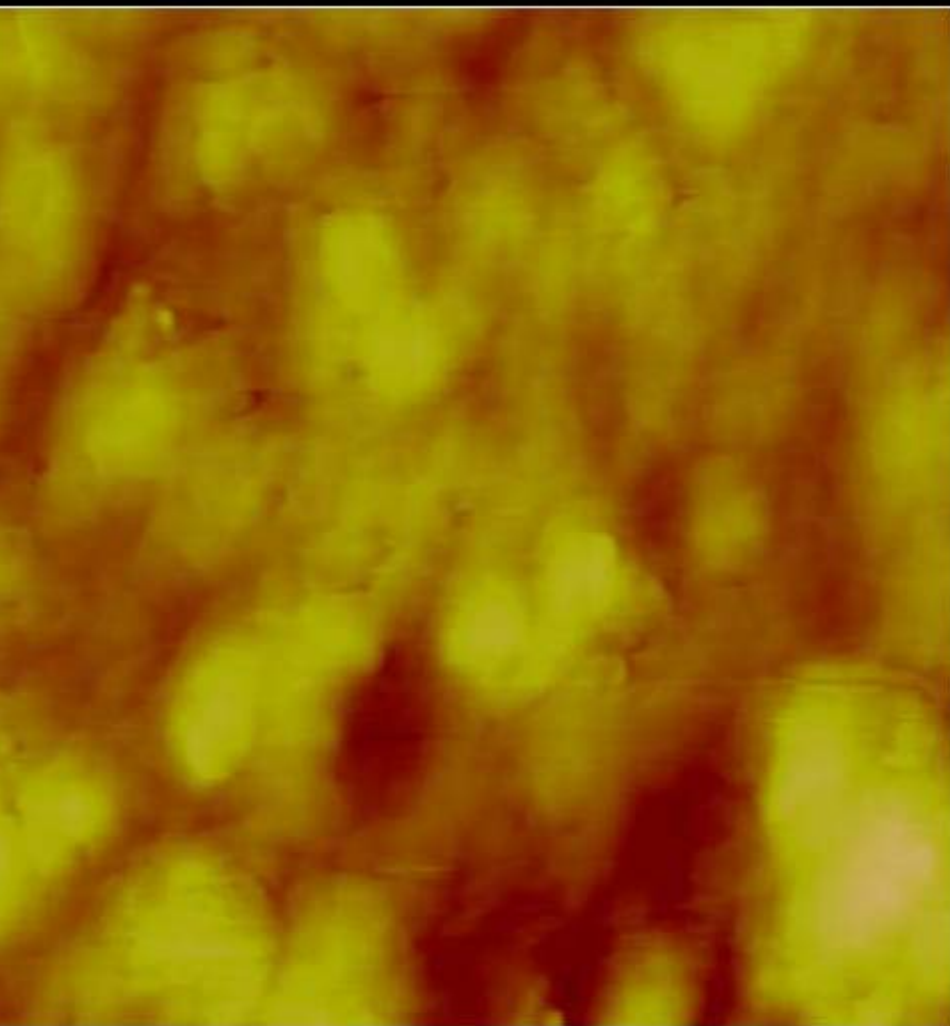


Data type Phase
Z range 180.0 °

1.00

osf1microndownht.003
/05 11% NCC in PSf down sample hard tapping

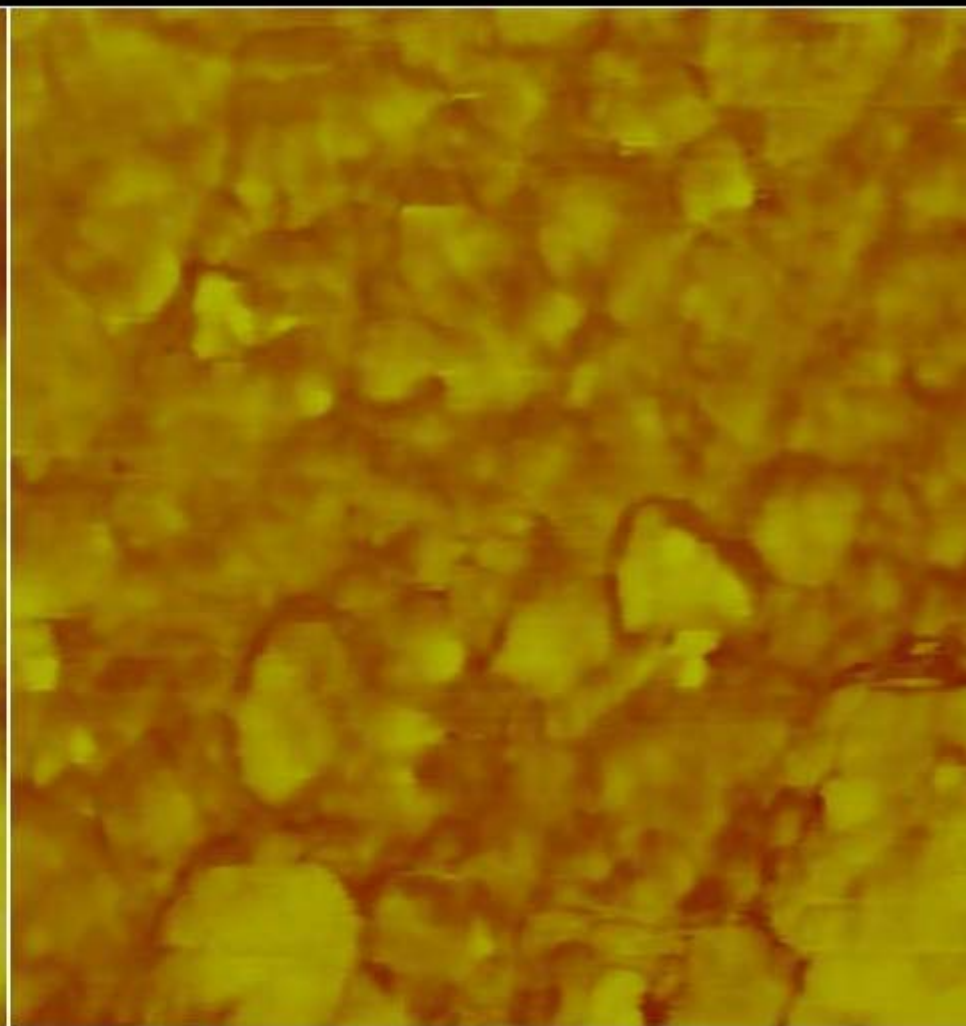
11% NCC, hard tapping



Data type
Z range

Height
20.00 nm

1.00 μm 0



Data type
Z range

Phase
180.0 °

1.00

psf1micron.000
/08 16% NCC in PSf

16% NCC

Roughness Analysis

$$R_{ms} = 1.9 \text{ nm}$$

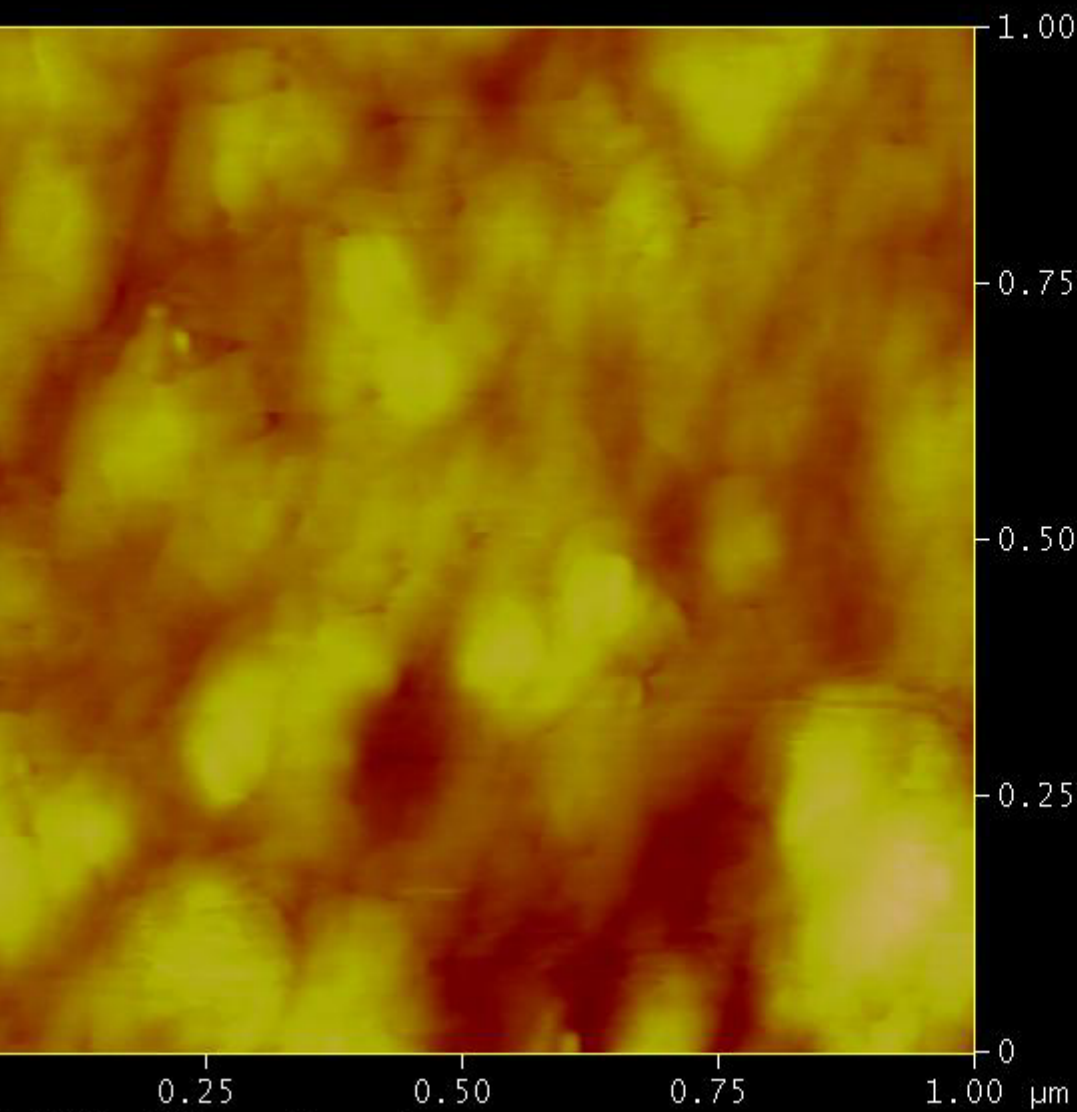


Image Statistics

Img. Z range	12.912 nm
Img. Mean	0.000000 nm
Img. Raw mean	633.59 nm
Img. Rms (Rq)	1.853 nm
Img. Ra	1.460 nm
Img. Rmax	12.912 nm
Img. Srf. area	1.003 μm^2
Img. Prj. Srf. area	999999 nm^2
Img. Srf. area diff	0.305 %
Img. SAE	1.001

Box Statistics

Z range
Mean
Raw mean
Rms (Rq)
Mean roughness (Ra)
Max height (Rmax)

16% NCC

CONCLUSIONS

- NCC can be dispersed in PSf
 - Quality of the dispersion is less than perfect
- NCC effects the T_g of the PSf
- TGA indicates 2% NCC in PSf behaves differently, close association?
- NCC stiffens, but does not strengthen composite
 - Interphase needs improvement
- Hard tapping on AFM has promise as technique to visualize
- Loadings of 16% cause dry out, poor properties

ACKNOWLEDGEMENTS

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